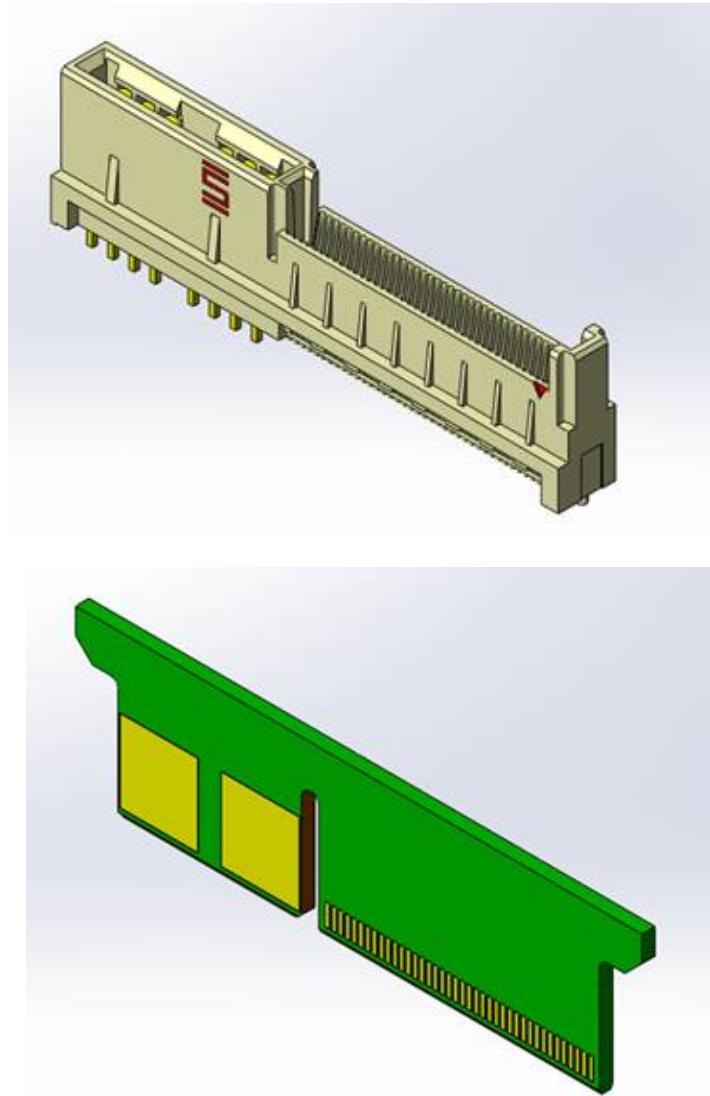


Project Number: Design Qualification Test Report	Tracking Code: 335190_Report_Rev_1
Requested by: Leo Lee	Date: 8/22/2014
Part #: HSEC8-140-01-L-PV-4-1-WT/Edge Card	
Part description: HSEC8/Edge Card	Tech: Kason He
Test Start: 6/4/2014	Test Completed: 8/20/2014

**DESIGN QUALIFICATION TEST REPORT**

HSEC8/Edge Card
HSEC8-140-01-L-PV-4-1-WT/Edge Card

REVISION HISTORY

DATA	REV.NUM.	DESCRIPTION	ENG
08/22/2014	1	Initial Issue	KH

CERTIFICATION

All instruments and measuring equipment were calibrated to National Institute for Standards and Technology (NIST) traceable standards according to ISO 10012-1 and ANSI/NCSL 2540-1, as applicable.

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SCOPE

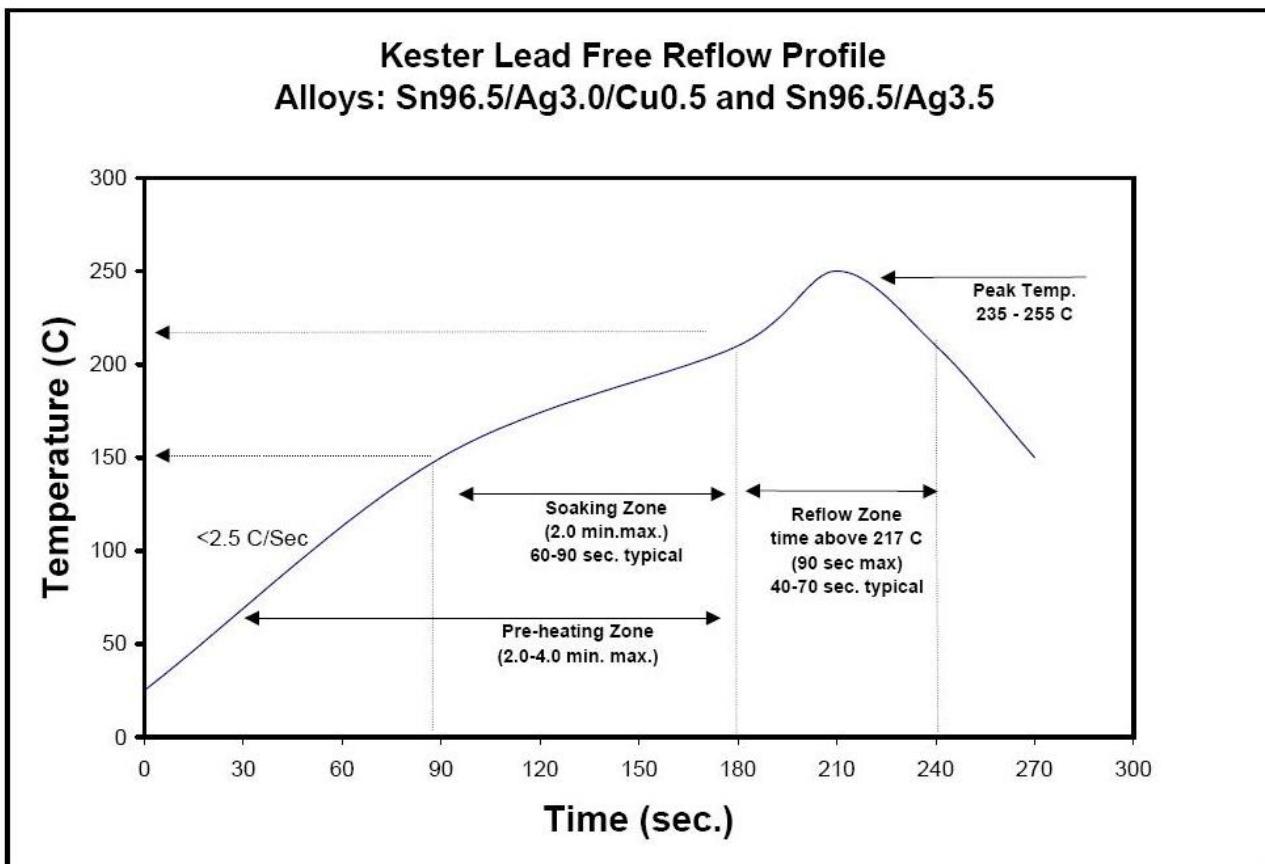
To perform the following tests: Design Qualification test. Please see test plan.

APPLICABLE DOCUMENTS

Standards: EIA Publication 364

TEST SAMPLES AND PREPARATION

- 1) All materials were manufactured in accordance with the applicable product specification.
- 2) All test samples were identified and encoded to maintain traceability throughout the test sequences.
- 3) After soldering, the parts to be used for LLCR testing were cleaned according to TLWI-0001.
- 4) Either an automated cleaning procedure or an ultrasonic cleaning procedure may be used.
- 5) The automated procedure is used with aqueous compatible soldering materials.
- 6) Parts not intended for testing LLCR are visually inspected and cleaned if necessary.
- 7) Any additional preparation will be noted in the individual test sequences.
- 8) Solder Information: Lead Free
- 9) Re-Flow Time/Temp: See accompanying profile.
- 10) Samtec Test PCBs used: PCB-106135-TST/PCB-106136-TST/PCB-106137-TST

TYPICAL OVEN PROFILE (Soldering Parts to Test Boards)

FLOWCHARTS

Gas Tight

Group 1

HSEC8-140-01-L-PV-4-1-WT

HSEC8-PC EDGE CARD

8 Assemblies

Note: 0.056" thick edge card(Min)

Step Description

1. LLCR ⁽²⁾
Max Delta = 15 mOhm
2. Gas Tight ⁽¹⁾
3. LLCR ⁽²⁾
Max Delta = 15 mOhm

(1) Gas Tight = EIA-364-36

(2) LLCR = EIA-364-23

Open Circuit Voltage = 20 mV Max

Test Current = 100 mA Max

Normal Force

Group 1

HSEC8-140-01-L-PV-4-1-WT

HSEC8-PC EDGE CARD

8 Contacts Minimum

Signal Without Thermals

Note: C-188-02

0.068" thick edge card(Max)

Group 2

HSEC8-140-01-L-PV-4-1-WT

HSEC8-PC EDGE CARD

8 Contacts Minimum

Signal With Thermals

Note: C-188-02

0.068" thick edge card(Max)

Group 3

HSEC8-140-01-L-PV-4-1-WT

HSEC8-PC EDGE CARD

8 Contacts Minimum

Power Without Thermals

Note: C-367-02

0.068" thick edge card(Max)

Group 4

HSEC8-140-01-L-PV-4-1-WT

HSEC8-PC EDGE CARD

8 Contacts Minimum

Power With Thermals

Note: C-367-02

0.068" thick edge card(Max)

Step Description

1. Contact Gaps
2. Normal Force ⁽¹⁾
Deflection = 0.023 "
Expected Force at Max Deflection = 72 g

Step Description

1. Contact Gaps
2. Thermal Age ⁽²⁾
3. Contact Gaps
4. Normal Force ⁽¹⁾
Deflection = 0.023 "
Expected Force at Max Deflection = 72 g

Step Description

1. Contact Gaps
2. Normal Force ⁽¹⁾
Deflection = 0.0098 "
Expected Force at Max Deflection = 442 g

Step Description

1. Contact Gaps
2. Thermal Age ⁽²⁾
3. Contact Gaps
4. Normal Force ⁽¹⁾
Deflection = 0.0098 "
Expected Force at Max Deflection = 442 g

(1) Normal Force = EIA-364-04

(2) Thermal Age = EIA-364-17

Test Condition = 4 (105 C)

Time Condition = B (250 Hours)

FLOWCHARTS Continued

Thermal Aging

Group 1

HSEC8-140-01-L-PV-4-1-WT

HSEC8-PC EDGE CARD

8 Assemblies

Note: 0.056" thick edge card(Min)

Step **Description**

1. Contact Gaps
2. Mating/Unmating Force ⁽²⁾
3. LLCR ⁽¹⁾
Max Delta = 15 mOhm
4. Thermal Age ⁽³⁾
5. LLCR ⁽¹⁾
Max Delta = 15 mOhm
6. Mating/Unmating Force ⁽²⁾
7. Contact Gaps

Group 2

HSEC8-140-01-L-PV-4-1-WT

HSEC8-PC EDGE CARD

8 Assemblies

Note: 0.068" thick edge card(max)

Step **Description**

1. Contact Gaps
2. Mating/Unmating Force ⁽²⁾
3. LLCR ⁽¹⁾
Max Delta = 15 mOhm
4. Thermal Age ⁽³⁾
5. LLCR ⁽¹⁾
Max Delta = 15 mOhm
6. Mating/Unmating Force ⁽²⁾
7. Contact Gaps

(1) LLCR = EIA-364-23

Open Circuit Voltage = 20 mV Max

Test Current = 100 mA Max

(2) Mating/Unmating Force = EIA-364-13

(3) Thermal Age = EIA-364-17

Test Condition = 4 (105 C)

Time Condition = B (250 Hours)

FLOWCHARTS Continued

Mating/Unmating/Durability

0.056" thick edge card(Min)

Group 1
HSEC8-140-01-L-PV-4-1-WT
HSEC8-PC EDGE CARD
8 Assemblies

Note: 0.056" thick edge card(Min)

Step	Description
1.	Contact Gaps
2.	LLCR (2) Max Delta = 15 mOhm
3.	Mating/Unmating Force (3)
4.	Cycles Quantity = 25 Cycles
5.	Mating/Unmating Force (3)
6.	Cycles Quantity = 25 Cycles
7.	Mating/Unmating Force (3)
8.	Cycles Quantity = 25 Cycles
9.	Mating/Unmating Force (3)
10.	Cycles Quantity = 25 Cycles
11.	Mating/Unmating Force (3)
12.	Contact Gaps
13.	LLCR (2) Max Delta = 15 mOhm
14.	Thermal Shock (4)
15.	LLCR (2) Max Delta = 15 mOhm
16.	Humidity (1)
17.	LLCR (2) Max Delta = 15 mOhm
18.	Mating/Unmating Force (3)

0.068" thick edge card(max)

Group 2
HSEC8-140-01-L-PV-4-1-WT
HSEC8-PC EDGE CARD
8 Assemblies

Note: 0.068" thick edge card(max)

Step	Description
1.	Contact Gaps
2.	LLCR (2) Max Delta = 15 mOhm
3.	Mating/Unmating Force (3)
4.	Cycles Quantity = 25 Cycles
5.	Mating/Unmating Force (3)
6.	Cycles Quantity = 25 Cycles
7.	Mating/Unmating Force (3)
8.	Cycles Quantity = 25 Cycles
9.	Mating/Unmating Force (3)
10.	Cycles Quantity = 25 Cycles
11.	Mating/Unmating Force (3)
12.	Contact Gaps
13.	LLCR (2) Max Delta = 15 mOhm
14.	Thermal Shock (4)
15.	LLCR (2) Max Delta = 15 mOhm
16.	Humidity (1)
17.	LLCR (2) Max Delta = 15 mOhm
18.	Mating/Unmating Force (3)

Group 3

HSEC8-120-01-L-PV-2-1-WT
HSEC8-PC EDGE CARD
8 Assemblies

Note: 0.068" thick edge card(max)

Step	Description
1.	Contact Gaps
2.	Mating/Unmating Force (3)
3.	Cycles Quantity = 25 Cycles
4.	Mating/Unmating Force (3)
5.	Cycles Quantity = 25 Cycles
6.	Mating/Unmating Force (3)
7.	Cycles Quantity = 25 Cycles
8.	Mating/Unmating Force (3)
9.	Cycles Quantity = 25 Cycles
10.	Mating/Unmating Force (3)
11.	Contact Gaps

Group 4

HSEC8-130-01-L-PV-2-1-WT
HSEC8-PC EDGE CARD
8 Assemblies

Note: 0.068" thick edge card(max)

Step	Description
1.	Contact Gaps
2.	Mating/Unmating Force (3)
3.	Cycles Quantity = 25 Cycles
4.	Mating/Unmating Force (3)
5.	Cycles Quantity = 25 Cycles
6.	Mating/Unmating Force (3)
7.	Cycles Quantity = 25 Cycles
8.	Mating/Unmating Force (3)
9.	Cycles Quantity = 25 Cycles
10.	Mating/Unmating Force (3)
11.	Contact Gaps

(1) Humidity = EIA-364-31

Test Condition = B (240 Hours)

Test Method = III (+25°C to +65°C @ 90% RH to 98% RH)

Test Exceptions: ambient pre-condition and delete steps 7a and 7b

(2) LLCR = EIA-364-23

Open Circuit Voltage = 20 mV Max

Test Current = 100 mA Max

(3) Mating/Unmating Force = EIA-364-13

(4) Thermal Shock = EIA-364-32

Exposure Time at Temperature Extremes = 1/2 Hour

Method A, Test Condition = I (-55°C to +85°C)

Test Duration = A-3 (100 Cycles)

FLOWCHARTS Continued

IR/DWV

Signal Pin-to-Pin

<u>Group 1</u>		<u>Group 2</u>		<u>Group 3</u>		<u>Group 4</u>	
HSEC8-140-01-L-PV-4-1-WT		HSEC8-140-01-L-PV-4-1-WT		HSEC8-PC EDGE CARD		HSEC8-140-01-L-PV-4-1-WT	
HSEC8-PC EDGE CARD		2 Assemblies		2 Assemblies		HSEC8-PC EDGE CARD	
2 Assemblies		2 Assemblies		2 Assemblies		2 Assemblies	
<i>Note: 0.056" thick edge card(Min)</i>		<i>Note: 0.056" thick edge card(Min)</i>		<i>Note: 0.056" thick edge card(Min)</i>		<i>Note: 0.056" thick edge card(Min)</i>	
Step	Description	Step	Description	Step	Description	Step	Description
1.	DWV Breakdown ⁽²⁾	1.	DWV Breakdown ⁽²⁾	1.	DWV Breakdown ⁽²⁾	1.	IR ⁽⁴⁾
							DWV at Test Voltage ⁽¹⁾
							Thermal Shock ⁽⁵⁾
							IR ⁽⁴⁾
							DWV at Test Voltage ⁽¹⁾
							Humidity ⁽³⁾
							IR ⁽⁴⁾
							DWV at Test Voltage ⁽¹⁾

Signal Row-to-Row

<u>Group 5</u>		<u>Group 6</u>		<u>Group 7</u>		<u>Group 8</u>	
HSEC8-140-01-L-PV-4-1-WT		HSEC8-140-01-L-PV-4-1-WT		HSEC8-PC EDGE CARD		HSEC8-140-01-L-PV-4-1-WT	
HSEC8-PC EDGE CARD		2 Assemblies		2 Assemblies		HSEC8-PC EDGE CARD	
2 Assemblies		2 Assemblies		2 Assemblies		2 Assemblies	
<i>Note: 0.056" thick edge card(Min)</i>		<i>Note: 0.056" thick edge card(Min)</i>		<i>Note: 0.056" thick edge card(Min)</i>		<i>Note: 0.056" thick edge card(Min)</i>	
Step	Description	Step	Description	Step	Description	Step	Description
1.	DWV Breakdown ⁽²⁾	1.	DWV Breakdown ⁽²⁾	1.	DWV Breakdown ⁽²⁾	1.	IR ⁽⁴⁾
							DWV at Test Voltage ⁽¹⁾
							Thermal Shock ⁽⁵⁾
							IR ⁽⁴⁾
							DWV at Test Voltage ⁽¹⁾
							Humidity ⁽³⁾
							IR ⁽⁴⁾
							DWV at Test Voltage ⁽¹⁾

FLOWCHARTS Continued

Signal-to-Power

Group 17

HSEC8-140-01-L-PV-4-1-WT
HSEC8-PC EDGE CARD
2 Assemblies

Note: 0.056" thick edge card(Min)

Step	Description
1.	DWV Breakdown (2)

Group 18

HSEC8-140-01-L-PV-4-1-WT
2 Assemblies

Note: 0.056" thick edge card(Min)

Step	Description
1.	DWV Breakdown (2)

Group 19

HSEC8-PC EDGE CARD
2 Assemblies

Note: 0.056" thick edge card(Min)

Step	Description
1.	DWV Breakdown (2)

Group 20

HSEC8-140-01-L-PV-4-1-WT
HSEC8-PC EDGE CARD
2 Assemblies

Note: 0.056" thick edge card(Min)

Step	Description
1.	IR (4)
2.	DWV at Test Voltage (1)
3.	Thermal Shock (5)
4.	IR (4)
5.	DWV at Test Voltage (1)
6.	Humidity (3)
7.	IR (4)
8.	DWV at Test Voltage (1)

(1) DWV at Test Voltage = EIA-364-20

Test Condition = 1 (Sea Level)

DWV test voltage is equal to 75% of the lowest breakdown voltage

Test voltage applied for 60 seconds

(2) DWV Breakdown = EIA-364-20

Test Condition = 1 (Sea Level)

DWV test voltage is equal to 75% of the lowest breakdown voltage

Test voltage applied for 60 seconds

(3) Humidity = EIA-364-31

Test Condition = B (240 Hours)

Test Method = III (+25°C to +65°C @ 90% RH to 98% RH)

Test Exceptions: ambient pre-condition and delete steps 7a and 7b

(4) IR = EIA-364-21

Test Condition = 500 Vdc, 2 Minutes Max

(5) Thermal Shock = EIA-364-32

Exposure Time at Temperature Extremes = 1/2 Hour

Method A, Test Condition = I (-55°C to +85°C)

Test Duration = A-3 (100 Cycles)

FLOWCHARTS Continued

Current Carrying Capacity

Group 1		Group 2		Group 3		Group 4	
HSEC8-140-01-L-PV-4-1-WT	HSEC8-140-01-L-PV-4-1-WT	HSEC8-140-01-L-PV-4-1-WT	HSEC8-140-01-L-PV-4-1-WT	HSEC8-140-01-L-PV-4-1-WT	HSEC8-140-01-L-PV-4-1-WT	HSEC8-140-01-L-PV-4-1-WT	HSEC8-140-01-L-PV-4-1-WT
HSEC8-PC EDGE CARD	HSEC8-PC EDGE CARD	HSEC8-PC EDGE CARD	HSEC8-PC EDGE CARD	HSEC8-PC EDGE CARD	HSEC8-PC EDGE CARD	HSEC8-PC EDGE CARD	HSEC8-PC EDGE CARD
2 Pins Powered	4 Pins Powered	6 Pins Powered	8 Pins Powered	Signal	Signal	Signal	Signal
Signal	Signal	Signal	Signal	Note: 0.056" thick edge card(Min)		Note: 0.056" thick edge card(Min)	
Step	Description	Step	Description	Step	Description	Step	Description
1.	CCC (2) Rows = 2 Number of Positions = 1	1.	CCC (2) Rows = 2 Number of Positions = 2	1.	CCC (2) Rows = 2 Number of Positions = 3	1.	CCC (2) Rows = 2 Number of Positions = 4
Group 5		Group 6		Group 7		Group 8	
HSEC8-140-01-L-PV-4-1-WT	HSEC8-140-01-L-PV-4-1-WT	HSEC8-140-01-L-PV-4-1-WT	HSEC8-140-01-L-PV-4-1-WT	HSEC8-140-01-L-PV-4-1-WT	HSEC8-140-01-L-PV-4-1-WT	HSEC8-140-01-L-PV-4-1-WT	HSEC8-140-01-L-PV-4-1-WT
HSEC8-PC EDGE CARD	HSEC8-PC EDGE CARD	HSEC8-PC EDGE CARD	HSEC8-PC EDGE CARD	HSEC8-PC EDGE CARD	HSEC8-PC EDGE CARD	HSEC8-PC EDGE CARD	HSEC8-PC EDGE CARD
80 Pins Powered	2 Pins Powered	4 Pins Powered	All Power	Power	Power	Power	All Power
Signal	Power	Power	Power	Note: 0.056" thick edge card(Min)		Note: Signal Pins @ 1/2 rated current from CCC sequence Group 5 Power Pins - All Contacts Powered 0.056" thick edge card(Min)	
Step	Description	Step	Description	Step	Description	Step	Description
1.	CCC (2) Rows = 2 Number of Positions = 40	1.	CCC (2) Rows = 2 Number of Positions = 1	1.	CCC (2) Rows = 2 Number of Positions = 2	1.	CCC - All Power (1)

(1) CCC - All Power = EIA-364-70

Method 2, Temperature Rise Versus Current Curve

(TIN PLATING) - Tabulate calculated current at RT, 65°C, 75°C and 95°C after derating 20% and based on 105°C

(GOLD PLATING) - Tabulate calculated current at RT, 85°C, 95°C and 115°C after derating 20% and based on 125°C

(2) CCC = EIA-364-70

Method 2, Temperature Rise Versus Current Curve

(TIN PLATING) - Tabulate calculated current at RT, 65°C, 75°C and 95°C after derating 20% and based on 105°C

(GOLD PLATING) - Tabulate calculated current at RT, 85°C, 95°C and 115°C after derating 20% and based on 125°C

FLOWCHARTS Continued

Mechanical Shock/Random Vibration/LLCR

0.056" thick edge card(Min)

Group 1

HSEC8-140-01-L-PV-4-1-WT

HSEC8-PC EDGE CARD

8 Assemblies

Note: 0.056" thick edge card(Min)

Step Description

1. LLCR₍₁₎
Max Delta = 15 mOhm
2. Mechanical Shock₍₂₎
3. Random Vibration₍₃₎
4. LLCR₍₁₎
Max Delta = 15 mOhm

0.068" thick edge card(max)

Group 2

HSEC8-140-01-L-PV-4-1-WT

HSEC8-PC EDGE CARD

8 Assemblies

Note: 0.068" thick edge card(max)

Step Description

1. LLCR₍₁₎
Max Delta = 15 mOhm
2. Mechanical Shock₍₂₎
3. Random Vibration₍₃₎
4. LLCR₍₁₎
Max Delta = 15 mOhm

(1) LLCR = EIA-364-23

Open Circuit Voltage = 20 mV Max
Test Current = 100 mA Max

(2) Mechanical Shock = EIA-364-27

Test Condition = C (100 G Peak, 6 milliseconds, Half Sine)
Number of Shocks = 3 Per Direction, Per Axis, 18 Total

(3) Random Vibration = EIA-364-28

Condition = VB (7.56 gRMS Average, 2 Hours/Axis)

FLOWCHARTS Continued

Mechanical Shock/Random Vibration/Event Detection

0.056" thick edge card(Min)

Group 1

HSEC8-140-01-L-PV-4-1-WT

HSEC8-PC EDGE CARD

60 Points

Note: 0.056" thick edge card(Min)

Step Description

1. Nanosecond Event Detection
(Mechanical Shock)⁽¹⁾
2. Nanosecond Event Detection
(Random Vibration)⁽²⁾

(1) Nanosecond Event Detection (Mechanical Shock)

Use EIA-364-87 for Nanosecond Event Detection:

Test Condition = F (50 nanoseconds at 10 ohms)

Use EIA-364-27 for Mechanical Shock:

Test Condition = C (100 G Peak, 6 milliseconds, Half Sine)

Number of Shocks = 3 Per Direction, Per Axis, 18 Total

(2) Nanosecond Event Detection (Random Vibration)

Use EIA-364-87 for Nanosecond Event Detection:

Test Condition = F (50 nanoseconds at 10 ohms)

Use EIA-364-28 for Random Vibration:

Condition = VB (7.56 gRMS Average, 2 Hours/Axis)

ATTRIBUTE DEFINITIONS

The following is a brief, simplified description of attributes.

THERMAL SHOCK:

- 1) EIA-364-32, *Thermal Shock (Temperature Cycling) Test Procedure for Electrical Connectors*.
- 2) Test Condition 1: -55°C to +85°C
- 3) Test Time: ½ hour dwell at each temperature extreme
- 4) Number of Cycles: 100
- 5) All test samples are pre-conditioned at ambient.
- 6) All test samples are exposed to environmental stressing in the mated condition.

THERMAL:

- 1) EIA-364-17, *Temperature Life with or without Electrical Load Test Procedure for Electrical Connectors*.
- 2) Test Condition 4 at 105° C
- 3) Test Time Condition B for 250 hours.
- 4) All test samples are pre-conditioned at ambient.
- 5) All test samples are exposed to environmental stressing in the mated condition.

HUMIDITY:

- 1) Reference document: EIA-364-31, *Humidity Test Procedure for Electrical Connectors*.
- 2) Test Condition B, 240 Hours.
- 3) Method III, +25° C to + 65° C, 90% to 98% Relative Humidity excluding sub-cycles 7a and 7b.
- 4) All samples are pre-conditioned at ambient.
- 5) All test samples are exposed to environmental stressing in the mated condition.

MECHANICAL SHOCK (Specified Pulse):

- 1) Reference document: EIA-364-27, *Mechanical Shock Test Procedure for Electrical Connectors*
- 2) Test Condition C
- 3) Peak Value: 100 G
- 4) Duration: 6 Milliseconds
- 5) Wave Form: Half Sine
- 6) Velocity: 12.3 ft/s
- 7) Number of Shocks: 3 Shocks / Direction, 3 Axis (18 Total)

VIBRATION:

- 1) Reference document: EIA-364-28, *Vibration Test Procedure for Electrical Connectors*
- 2) Test Condition V, Letter B
- 3) Power Spectral Density: 0.04 G² / Hz
- 4) G 'RMS': 7.56
- 5) Frequency: 50 to 2000 Hz
- 6) Duration: 2.0 Hours per axis (3 axis total)

NANOSECOND-EVENT DETECTION:

- 1) Reference document: EIA-364-87, *Nanosecond-Event Detection for Electrical Connectors*
- 2) Prior to test, the samples were characterized to assure the low nanosecond event being monitored will trigger the detector.
- 3) After characterization it was determined the test samples could be monitored for 50 nanosecond events

MATING/UNMATING:

- 1) Reference document: EIA-364-13, *Mating and Unmating Forces Test Procedure for Electrical Connectors*.
- 2) The full insertion position was to within 0.003" to 0.004" of the plug bottoming out in the receptacle to prevent damage to the system under test.
- 3) One of the mating parts is secured to a floating X-Y table to prevent damage during cycling.

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes.

TEMPERATURE RISE (Current Carrying Capacity, CCC):

- 1) EIA-364-70, *Temperature Rise versus Current Test Procedure for Electrical Connectors and Sockets*.
- 2) When current passes through a contact, the temperature of the contact increases as a result of I^2R (resistive) heating.
- 3) The number of contacts being investigated plays a significant part in power dissipation and therefore temperature rise.
- 4) The size of the temperature probe can affect the measured temperature.
- 5) Copper traces on PC boards will contribute to temperature rise:
 - a. Self heating (resistive)
 - b. Reduction in heat sink capacity affecting the heated contacts
- 6) A de-rating curve, usually 20%, is calculated.
- 7) Calculated de-rated currents at three temperature points are reported:
 - a. Ambient
 - b. 85°C
 - c. 95°C
 - d. 115°C
- 8) Typically, neighboring contacts (in close proximity to maximize heat build up) are energized.
- 9) The thermocouple (or temperature measuring probe) will be positioned at a location to sense the maximum temperature in the vicinity of the heat generation area.
- 10) A computer program, *TR 803.exe*, ensures accurate stability for data acquisition.
- 11) Hook-up wire cross section is larger than the cross section of any connector leads/PC board traces, jumpers, etc.
- 12) Hook-up wire length is longer than the minimum specified in the referencing standard.

LLCR:

- 1) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 2) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 3) The following guidelines are used to categorize the changes in LLCR as a result from stressing
 - a. $\leq +5.0 \text{ mOhms}$: ----- Stable
 - b. $+5.1 \text{ to } +10.0 \text{ mOhms}$: ----- Minor
 - c. $+10.1 \text{ to } +15.0 \text{ mOhms}$: ----- Acceptable
 - d. $+15.1 \text{ to } +50.0 \text{ mOhms}$: ----- Marginal
 - e. $+50.1 \text{ to } +2000 \text{ mOhms}$: ----- Unstable
 - f. $>+2000 \text{ mOhms}$: ----- Open Failure

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes.

GAS TIGHT:

To provide method for evaluating the ability of the contacting surfaces in preventing penetration of harsh vapors which might lead to oxide formation that may degrade the electrical performance of the contact system.

- 1) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 2) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 3) The following guidelines are used to categorize the changes in LLCR as a result from stressing
 - a. $\leq +5.0$ mOhms: ----- Stable
 - b. $+5.1$ to $+10.0$ mOhms: ----- Minor
 - c. $+10.1$ to $+15.0$ mOhms: ----- Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: ----- Marginal
 - e. $+50.1$ to $+2000$ mOhms: ----- Unstable
 - f. $>+2000$ mOhms: ----- Open Failure
- 4) Procedure:
 - a. Reference document: EIA-364-36, *Test Procedure for Determination of Gas-Tight Characteristics for Electrical Connectors, Sockets and/or Contact Systems*.
 - b. Test Conditions:
 - i. Class II--- Mated pairs of contacts assembled to their plastic housings.
 - ii. Reagent grade Nitric Acid shall be used of sufficient volume to saturate the test chamber
 - iii. The ratio of the volume of the test chamber to the surface area of the acid shall be 10:1.
 - iv. The chamber shall be saturated with the vapor for at least 15 minutes before samples are added.
 - v. Exposure time, 55 to 65 minutes.
 - vi. The samples shall be no closer to the chamber walls than 1 inches and no closer to the surface of the acid than 3 inches.
 - vii. The samples shall be dried after exposure for a minimum of 1 hour.
 - viii. Drying temperature 50°C
 - ix. The final LLCR shall be conducted within 1 hour after drying.

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes

NORMAL FORCE (FOR CONTACTS TESTED IN THE HOUSING):

- 1) Reference document: EIA-364-04, *Normal Force Test Procedure for Electrical Connectors*.
- 2) The contacts shall be tested in the connector housing.
- 3) If necessary, a “window” shall be made in the connector body to allow a probe to engage and deflect the contact at the same attitude and distance (plus 0.05 mm [0.002”]) as would occur in actual use.
- 4) The connector housing shall be placed in a holding fixture that does not interfere with or otherwise influence the contact force or deflection.
- 5) Said holding fixture shall be mounted on a floating, adjustable, X-Y table on the base of the Dillon TC², computer controlled test stand with a deflection measurement system accuracy of 5.0 μm (0.0002”).
- 6) The nominal deflection rate shall be 5 mm (0.2”)/minute.
- 7) Unless otherwise noted a minimum of five contacts shall be tested.
- 8) The force/deflection characteristic to load and unload each contact shall be repeated five times.
- 9) The system shall utilize the TC² software in order to acquire and record the test data.
- 10) The permanent set of each contact shall be measured within the TC² software.
- 11) The acquired data shall be graphed with the deflection data on the X-axis and the force data on the Y-axis and a print out will be stored with the Tracking Code paperwork.

INSULATION RESISTANCE (IR):

To determine the resistance of insulation materials to leakage of current through or on the surface of these materials when a DC potential is applied.

- 1) PROCEDURE:
 - a. Reference document: EIA-364-21, *Insulation Resistance Test Procedure for Electrical Connectors*.
 - b. Test Conditions:
 - i. Between Adjacent Contacts or Signal-to-Ground
 - ii. Electrification Time 2.0 minutes
 - iii. Test Voltage (500 VDC) corresponds to calibration settings for measuring resistances.
- 2) MEASUREMENTS:
- 3) When the specified test voltage is applied (VDC), the insulation resistance shall not be less than 1000 megohms.

DIELECTRIC WITHSTANDING VOLTAGE (DWV):

To determine if the sockets can operate at its rated voltage and withstand momentary over potentials due to switching, surges, and other similar phenomenon. Separate samples are used to evaluate the effect of environmental stresses so not to influence the readings from arcing that occurs during the measurement process.

- 1) PROCEDURE:
 - a. Reference document: EIA-364-20, *Withstanding Voltage Test Procedure for Electrical Connectors*.
 - b. Test Conditions:
 - i. Between Adjacent Contacts or Signal-to-Ground
 - ii. Barometric Test Condition 1
 - iii. Rate of Application 500 V/Sec
 - iv. Test Voltage (VAC) until breakdown occurs
- 2) MEASUREMENTS/CALCULATIONS
 - a. The breakdown voltage shall be measured and recorded.
 - b. The dielectric withstand voltage shall be recorded as 75% of the minimum breakdown voltage.
 - c. The working voltage shall be recorded as one-third (1/3) of the dielectric withstand voltage (one-fourth of the breakdown voltage).

RESULTS

Temperature Rise, CCC at a 20% de-rating

Signal pin

- CCC for a 30°C Temperature Rise ----- 3.2 A per contact with 2 contacts (2 x 1) powered
- CCC for a 30°C Temperature Rise ----- 2.7 A per contact with 4 contacts (2 x 2) powered
- CCC for a 30°C Temperature Rise ----- 2.0 A per contact with 6 contacts (2 x 3) powered
- CCC for a 30°C Temperature Rise ----- 1.8 A per contact with 8 contacts (2 x 4) powered
- CCC for a 30°C Temperature Rise ----- 0.9 A per contact with 80 contacts (2 x 40) powered

Power pin

- CCC for a 30°C Temperature Rise ----- 27.5 A per contact with 2 contacts (2 x 1) powered
- CCC for a 30°C Temperature Rise ----- 23.9 A per contact with 4 contacts (2 x 2) powered

Power pin and Signal pin (signal contacts powered @ 1/2 rated current @ .6 AMPS)

- CCC for a 30°C Temperature Rise ----- 23.0 A per contact with 4 contacts (2 x 2) powered

Mating/Unmating Forces

Thermal Aging Group

Edge Card 0.056"

- Initial
 - Mating
 - Min ----- 8.00 Lbs
 - Max ----- 9.71 Lbs
 - Unmating
 - Min ----- 4.52 Lbs
 - Max ----- 5.73 Lbs
- After Thermal
 - Mating
 - Min ----- 6.77 Lbs
 - Max ----- 8.54 Lbs
 - Unmating
 - Min ----- 4.35 Lbs
 - Max ----- 5.23 Lbs

Edge Card 0.068"

- Initial
 - Mating
 - Min ----- 11.14 Lbs
 - Max ----- 13.51 Lbs
 - Unmating
 - Min ----- 6.19 Lbs
 - Max ----- 8.29 Lbs
- After Thermal
 - Mating
 - Min ----- 8.10 Lbs
 - Max ----- 10.24 Lbs
 - Unmating
 - Min ----- 4.58 Lbs
 - Max ----- 5.57 Lbs

RESULTS Continued

Mating/Unmating Forces

Mating-Unmating Durability (HSEC8-140-01-L-PV-4-1-WT/Edge Card 0.056")

- Initial
 - Mating
 - Min ----- 7.49 Lbs
 - Max ----- 9.15 Lbs
 - Unmating
 - Min ----- 4.17 Lbs
 - Max ----- 4.81 Lbs
- After 25 Cycles
 - Mating
 - Min ----- 9.60 Lbs
 - Max ----- 11.61 Lbs
 - Unmating
 - Min ----- 5.08 Lbs
 - Max ----- 6.01 Lbs
- After 50 Cycles
 - Mating
 - Min ----- 10.72 Lbs
 - Max ----- 12.30 Lbs
 - Unmating
 - Min ----- 5.84 Lbs
 - Max ----- 6.49 Lbs
- After 75 Cycles
 - Mating
 - Min ----- 11.84 Lbs
 - Max ----- 12.78 Lbs
 - Unmating
 - Min ----- 6.38 Lbs
 - Max ----- 7.21 Lbs
- After 100 Cycles
 - Mating
 - Min ----- 12.32 Lbs
 - Max ----- 13.94 Lbs
 - Unmating
 - Min ----- 6.68 Lbs
 - Max ----- 7.84 Lbs
- Humidity
 - Mating
 - Min ----- 5.38 Lbs
 - Max ----- 8.32 Lbs
 - Unmating
 - Min ----- 3.05 Lbs
 - Max ----- 5.41 Lbs

RESULTS Continued

Mating/Unmating Forces

Mating-Unmating Durability (HSEC8-140-01-L-PV-4-1-WT/Edge Card 0.068")

- Initial
 - Mating
 - Min ----- 9.55 Lbs
 - Max ----- 11.19 Lbs
 - Unmating
 - Min ----- 4.71 Lbs
 - Max ----- 5.66 Lbs
- After 25 Cycles
 - Mating
 - Min ----- 11.44 Lbs
 - Max ----- 12.78 Lbs
 - Unmating
 - Min ----- 5.84 Lbs
 - Max ----- 6.91 Lbs
- After 50 Cycles
 - Mating
 - Min ----- 12.36 Lbs
 - Max ----- 13.97 Lbs
 - Unmating
 - Min ----- 6.94 Lbs
 - Max ----- 7.88 Lbs
- After 75 Cycles
 - Mating
 - Min ----- 13.24 Lbs
 - Max ----- 14.91 Lbs
 - Unmating
 - Min ----- 7.50 Lbs
 - Max ----- 8.64 Lbs
- After 100 Cycles
 - Mating
 - Min ----- 14.17 Lbs
 - Max ----- 15.77 Lbs
 - Unmating
 - Min ----- 7.63 Lbs
 - Max ----- 9.37 Lbs
- Humidity
 - Mating
 - Min ----- 7.07 Lbs
 - Max ----- 10.05 Lbs
 - Unmating
 - Min ----- 4.22 Lbs
 - Max ----- 6.64 Lbs

RESULTS Continued

Mating/Unmating Forces

Mating-Unmating Basic (HSEC8-120-01-L-PV-2-1-WT/Edge Card 0.068")

- Initial
 - Mating
 - Min ----- 5.11 Lbs
 - Max ----- 5.74 Lbs
 - Unmating
 - Min ----- 2.39 Lbs
 - Max ----- 2.83 Lbs
- After 25 Cycles
 - Mating
 - Min ----- 5.03 Lbs
 - Max ----- 6.29 Lbs
 - Unmating
 - Min ----- 2.83 Lbs
 - Max ----- 3.72 Lbs
- After 50 Cycles
 - Mating
 - Min ----- 5.17 Lbs
 - Max ----- 6.38 Lbs
 - Unmating
 - Min ----- 3.06 Lbs
 - Max ----- 4.02 Lbs
- After 75 Cycles
 - Mating
 - Min ----- 5.10 Lbs
 - Max ----- 6.39 Lbs
 - Unmating
 - Min ----- 3.18 Lbs
 - Max ----- 4.31 Lbs
- After 100 Cycles
 - Mating
 - Min ----- 5.10 Lbs
 - Max ----- 6.47 Lbs
 - Unmating
 - Min ----- 3.18 Lbs
 - Max ----- 4.53 Lbs

RESULTS Continued

Mating/Unmating Forces

Mating-Unmating Basic (HSEC8-130-01-L-PV-2-1-WT/Edge Card 0.068")

- Initial
 - Mating
 - Min ----- 7.20 Lbs
 - Max ----- 8.07 Lbs
 - Unmating
 - Min ----- 3.18 Lbs
 - Max ----- 3.61 Lbs
- After 25 Cycles
 - Mating
 - Min ----- 7.49 Lbs
 - Max ----- 8.62 Lbs
 - Unmating
 - Min ----- 3.63 Lbs
 - Max ----- 4.70 Lbs
- After 50 Cycles
 - Mating
 - Min ----- 7.60 Lbs
 - Max ----- 8.67 Lbs
 - Unmating
 - Min ----- 3.96 Lbs
 - Max ----- 5.11 Lbs
- After 75 Cycles
 - Mating
 - Min ----- 7.65 Lbs
 - Max ----- 8.69 Lbs
 - Unmating
 - Min ----- 4.11 Lbs
 - Max ----- 5.21 Lbs
- After 100 Cycles
 - Mating
 - Min ----- 7.69 Lbs
 - Max ----- 8.71 Lbs
 - Unmating
 - Min ----- 4.19 Lbs
 - Max ----- 5.42 Lbs

RESULTS Continued

Normal Force at 0.0223 inches deflection

C-188-02 Signal pin

• Initial	○ Min -----	78.00 gf	Set ----- 0.0045 inch
	○ Max -----	82.20 gf	Set ----- 0.0051 inch
• Thermal	○ Min -----	67.70 gf	Set ----- 0.0050 inch
	○ Max -----	74.30 gf	Set ----- 0.0057 inch

Normal Force at 0.0153 inches deflection

C-367-02 Power pin - left

• Initial	○ Min -----	668.70 gf	Set ----- 0.0003 inch
	○ Max -----	735.60 gf	Set ----- 0.0010 inch
• Thermal	○ Min -----	351.50 gf	Set ----- 0.0068 inch
	○ Max -----	450.10 gf	Set ----- 0.0082 inch

C-367-02 Power pin - middle

• Initial	○ Min -----	617.90 gf	Set ----- 0.0002 inch
	○ Max -----	705.50 gf	Set ----- 0.0008 inch
• Thermal	○ Min -----	348.20 gf	Set ----- 0.0068 inch
	○ Max -----	429.90 gf	Set ----- 0.0078 inch

C-367-02 Power pin - right

• Initial	○ Min -----	644.90 gf	Set ----- 0.0002 inch
	○ Max -----	733.00 gf	Set ----- 0.0008 inch
• Thermal	○ Min -----	360.80 gf	Set ----- 0.0073 inch
	○ Max -----	406.90 gf	Set ----- 0.0081 inch

RESULTS Continued

Insulation Resistance minimums, IR

Pin to Pin Signal

- **Initial**
 - Mated ----- 10000 Meg Ω ----- Passed
 - Unmated ----- 10000 Meg Ω ----- Passed
- **Thermal Shock**
 - Mated ----- 10000 Meg Ω ----- Passed
 - Unmated ----- 10000 Meg Ω ----- Passed
- **Humidity**
 - Mated ----- 10000 Meg Ω ----- Passed
 - Unmated ----- 10000 Meg Ω ----- Passed

Row to Row Signal

- **Initial**
 - Mated ----- 10000 Meg Ω ----- Passed
 - Unmated ----- 10000 Meg Ω ----- Passed
- **Thermal Shock**
 - Mated ----- 10000 Meg Ω ----- Passed
 - Unmated ----- 10000 Meg Ω ----- Passed
- **Humidity**
 - Mated ----- 10000 Meg Ω ----- Passed
 - Unmated ----- 10000 Meg Ω ----- Passed

Signal to Power

- **Initial**
 - Mated ----- 10000 Meg Ω ----- Passed
 - Unmated ----- 10000 Meg Ω ----- Passed
- **Thermal Shock**
 - Mated ----- 10000 Meg Ω ----- Passed
 - Unmated ----- 10000 Meg Ω ----- Passed
- **Humidity**
 - Mated ----- 10000 Meg Ω ----- Passed
 - Unmated ----- 10000 Meg Ω ----- Passed

Pin to Pin Power

- **Initial**
 - Mated ----- 10000 Meg Ω ----- Passed
 - Unmated ----- 10000 Meg Ω ----- Passed
- **Thermal Shock**
 - Mated ----- 10000 Meg Ω ----- Passed
 - Unmated ----- 10000 Meg Ω ----- Passed
- **Humidity**
 - Mated ----- 10000 Meg Ω ----- Passed
 - Unmated ----- 10000 Meg Ω ----- Passed

Row to Row Power

- **Initial**
 - Mated ----- 10000 Meg Ω ----- Passed
 - Unmated ----- 10000 Meg Ω ----- Passed
- **Thermal Shock**
 - Mated ----- 10000 Meg Ω ----- Passed
 - Unmated ----- 10000 Meg Ω ----- Passed
- **Humidity**
 - Mated ----- 10000 Meg Ω ----- Passed
 - Unmated ----- 10000 Meg Ω ----- Passed

RESULTS Continued

Dielectric Withstanding Voltage minimums, DWV

- **Minumums**

- **Breakdown Voltage**-----875 VAC
- **Test Voltage** -----660 VAC
- **Working Voltage** -----215 VAC

Pin to Pin Signal

- **Initial DWV** -----Passed
- **Thermal DWV**-----Passed
- **Humidity DWV**-----Passed

Row to Row Signal

- **Initial DWV** -----Passed
- **Thermal DWV**-----Passed
- **Humidity DWV**-----Passed

Signal to Power

- **Initial DWV** -----Passed
- **Thermal DWV**-----Passed
- **Humidity DWV**-----Passed

Pin to Pin Power

- **Initial DWV** -----Passed
- **Thermal DWV**-----Passed
- **Humidity DWV**-----Passed

Row to Row Power

- **Initial DWV** -----Passed
- **Thermal DWV**-----Passed
- **Humidity DWV**-----Passed

RESULTS Continued

LLCR Thermal Aging Group (160 signal and 32 power LLCR test points)

Edge Card 0.056"

Signal pin

- Initial ----- 7.83 mOhms Max
- Thermal
 - <= +5.0 mOhms ----- 155 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 5 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure

Power pin

- Initial ----- 0.28 mOhms Max
- Thermal
 - <= +5.0 mOhms ----- 32 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure

Edge Card 0.068"

Signal pin

- Initial ----- 7.81 mOhms Max
- Thermal
 - <= +5.0 mOhms ----- 160 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure

Power pin

- Initial ----- 0.26 mOhms Max
- Thermal
 - <= +5.0 mOhms ----- 32 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure

RESULTS Continued

LLCR Gas Tight Group (160 signal and 32 power LLCR test points)

Edge Card 0.056"

Signal pin

- Initial ----- 9.20 mOhms Max
- Thermal
 - <= +5.0 mOhms ----- 160 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure

Power pin

- Initial ----- 0.30 mOhms Max
- Thermal
 - <= +5.0 mOhms ----- 32 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure

RESULTS Continued

LLCR Mating/Unmating Durability Group (160 signal and 32 power LLCR test points) Edge Card 0.056"

Signal pin

- Initial ----- 8.98 mOhms Max
- Durability, 100 Cycles
 - <= +5.0 mOhms ----- 160 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure
- Thermal Shock
 - <= +5.0 mOhms ----- 160 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure
- Humidity
 - <= +5.0 mOhms ----- 146 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 14 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure

Power pin

- Initial ----- 0.30 mOhms Max
- Durability, 100 Cycles
 - <= +5.0 mOhms ----- 32 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure
- Thermal Shock
 - <= +5.0 mOhms ----- 32 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure
- Humidity
 - <= +5.0 mOhms ----- 32 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure

RESULTS Continued

LLCR Mating/Unmating Durability Group (160 signal and 32 power LLCR test points) Edge Card 0.068"

Signal pin

- Initial ----- 10.00 mOhms Max
- Durability, 100 Cycles
 - <= +5.0 mOhms ----- 160 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure
- Thermal Shock
 - <= +5.0 mOhms ----- 160 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure
- Humidity
 - <= +5.0 mOhms ----- 147 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 13 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure

Power pin

- Initial ----- 0.27 mOhms Max
- Durability, 100 Cycles
 - <= +5.0 mOhms ----- 32 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure
- Thermal Shock
 - <= +5.0 mOhms ----- 32 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure
- Humidity
 - <= +5.0 mOhms ----- 32 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure

RESULTS Continued

LLCR Shock & Vibration Group (160 signal and 32 power LLCR test points)

Edge Card 0.056"

Signal pin

- Initial ----- **9.81 mOhms Max**
- Shock & Vibration
 - <= +5.0 mOhms ----- 160 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure

Power pin

- Initial ----- 0.37 mOhms Max
- Shock & Vibration
 - <= +5.0 mOhms ----- 32 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure

Edge Card 0.068"

Signal pin

- Initial ----- 8.31 mOhms Max
- Shock & Vibration
 - <= +5.0 mOhms ----- 160 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure

Power pin

- Initial ----- 0.33 mOhms Max
- Shock & Vibration
 - <= +5.0 mOhms ----- 32 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure

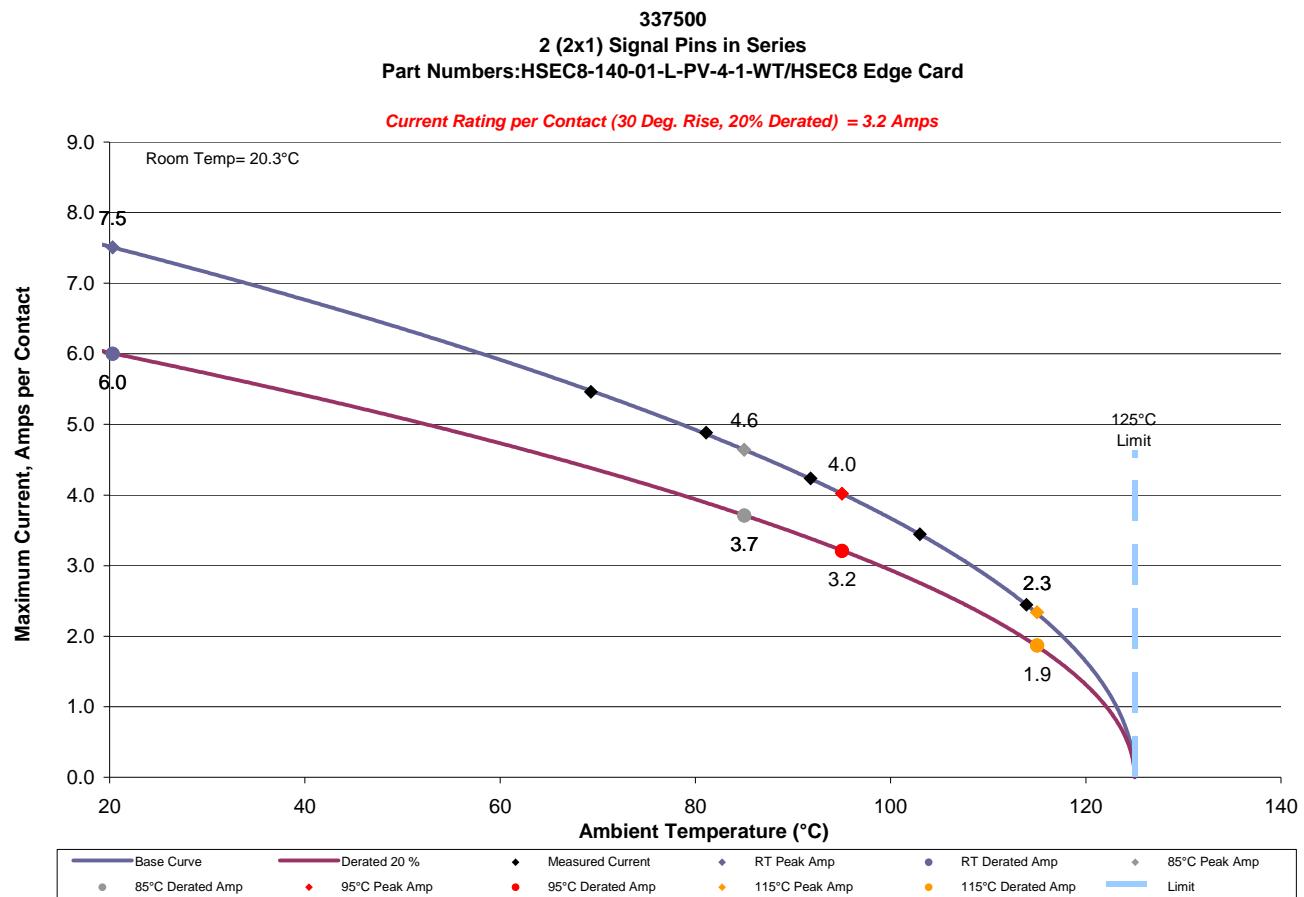
Mechanical Shock & Random Vibration:

- Shock
 - No Damage----- Passed
 - 50 Nanoseconds----- Passed
- Vibration
 - No Damage----- Passed
 - 50 Nanoseconds----- Passed

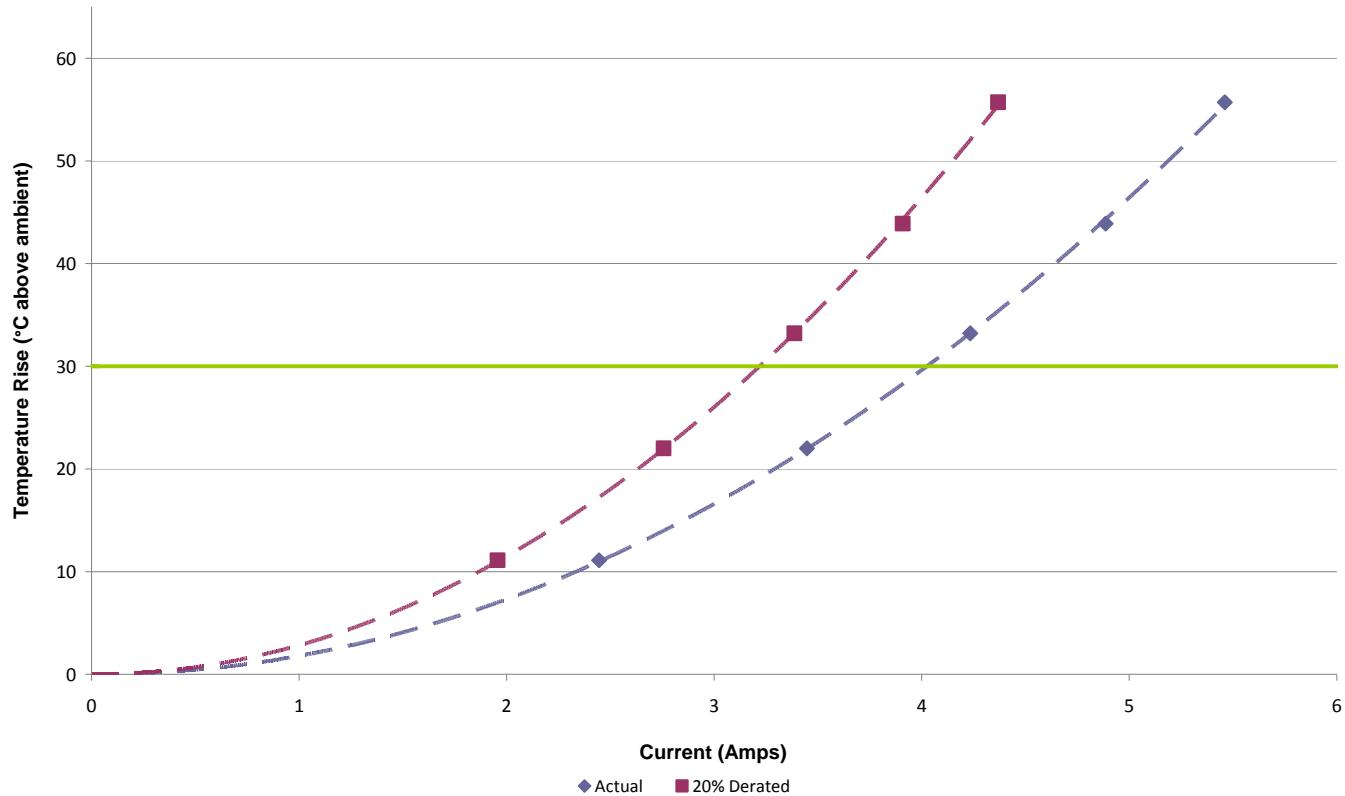
DATA SUMMARIES

TEMPERATURE RISE (Current Carrying Capacity, CCC):

- 1) High quality thermocouples whose temperature slopes track one another were used for temperature monitoring.
- 2) The thermocouples were placed at a location to sense the maximum temperature generated during testing.
- 3) Temperature readings recorded are those for which three successive readings, 15 minutes apart, differ less than 1°C (computer controlled data acquisition).
- 4) Adjacent contacts were powered:
 - a. Linear configuration with 2 adjacent signal conductors/contacts powered

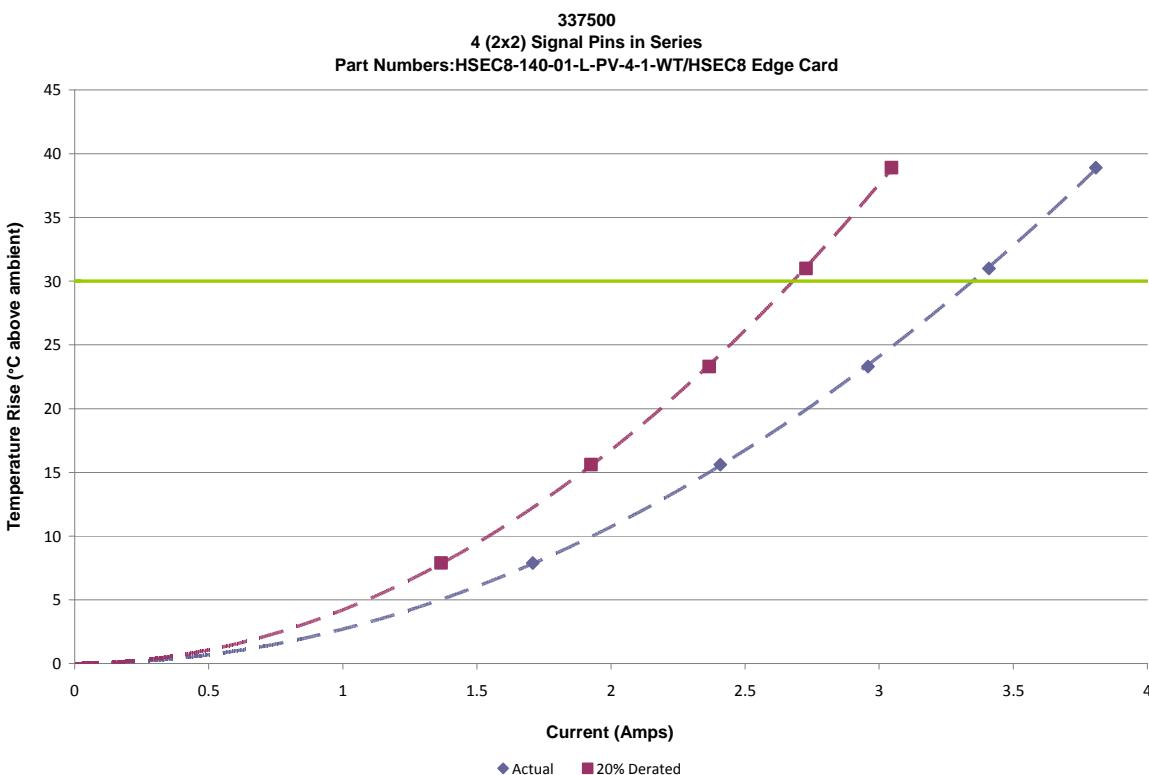
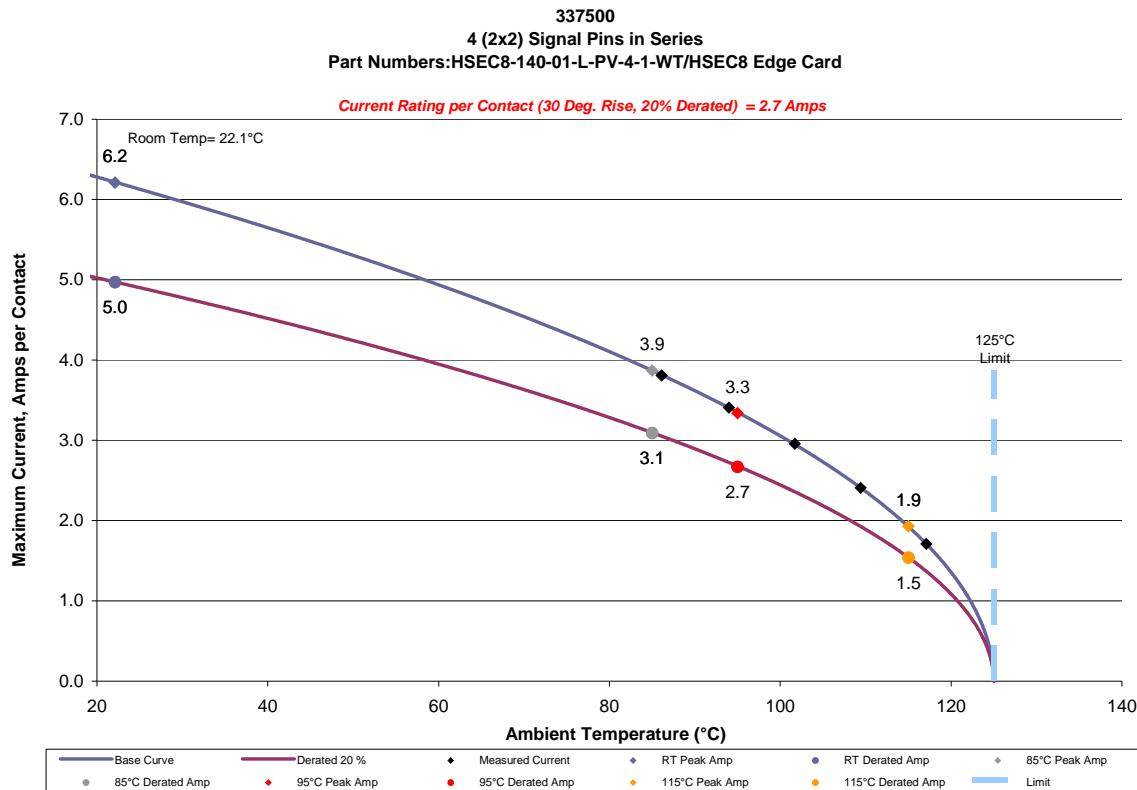


337500
2 (2x1) Signal Pins in Series
Part Numbers:HSEC8-140-01-L-PV-4-1-WT/HSEC8 Edge Card



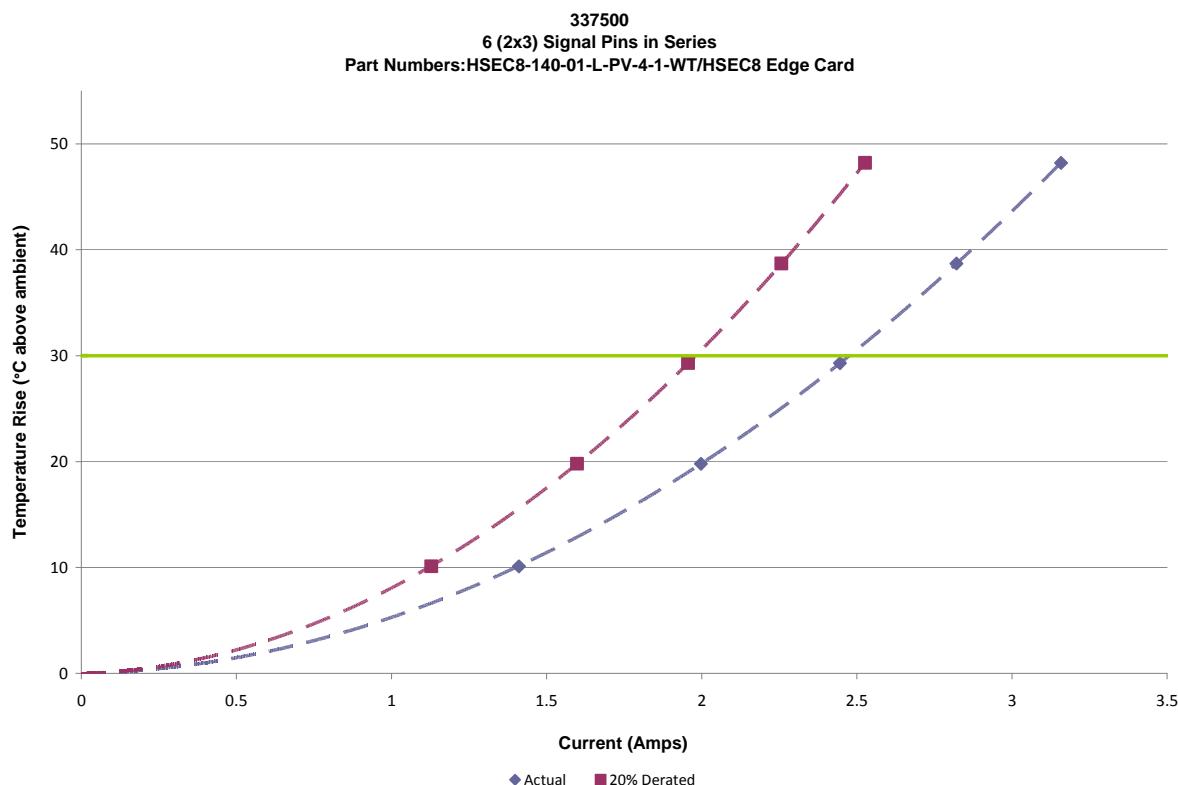
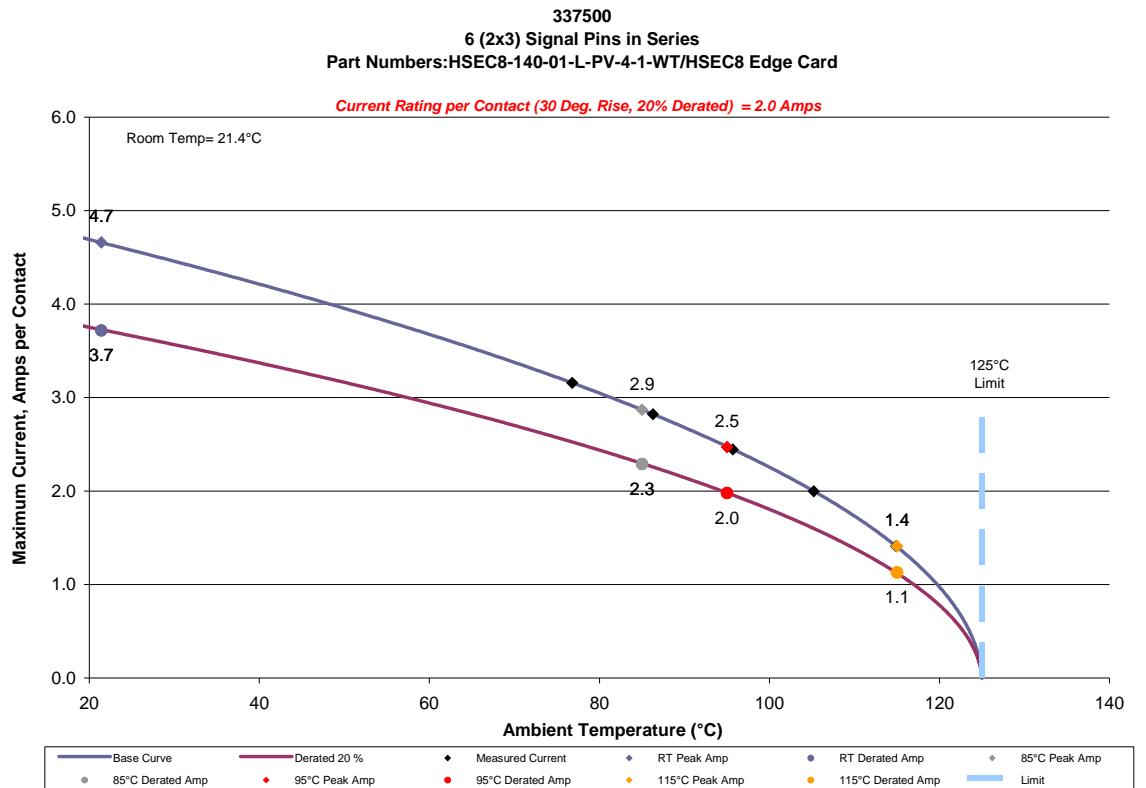
DATA SUMMARIES Continued

b. Linear configuration with 4 adjacent signal conductors/contacts powered



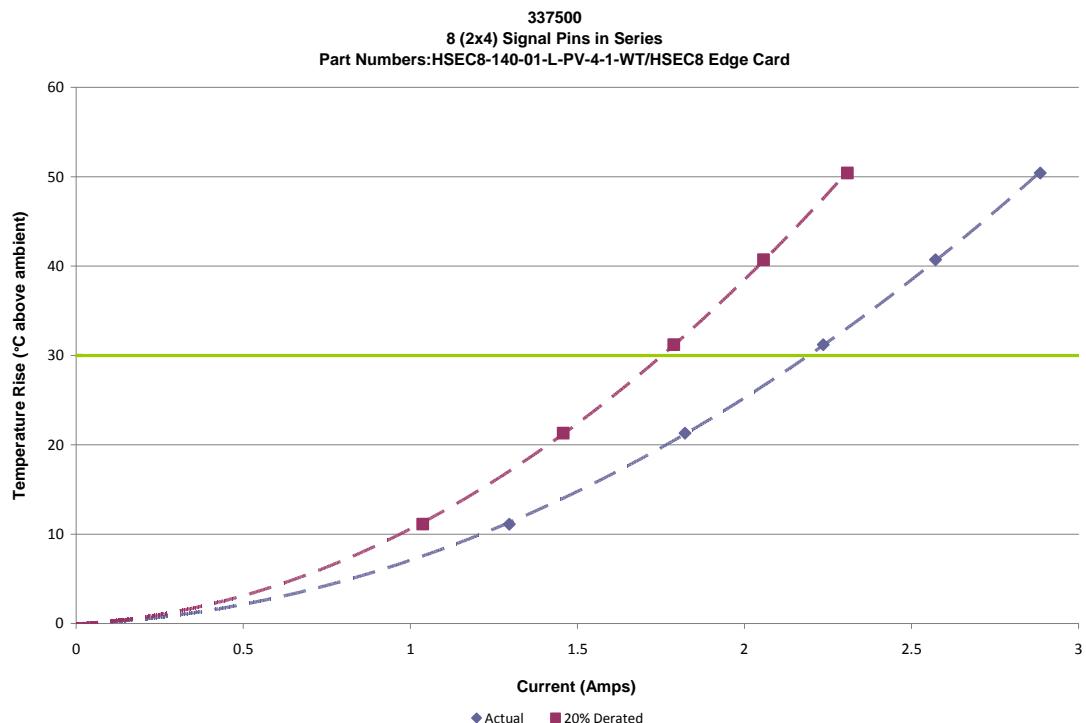
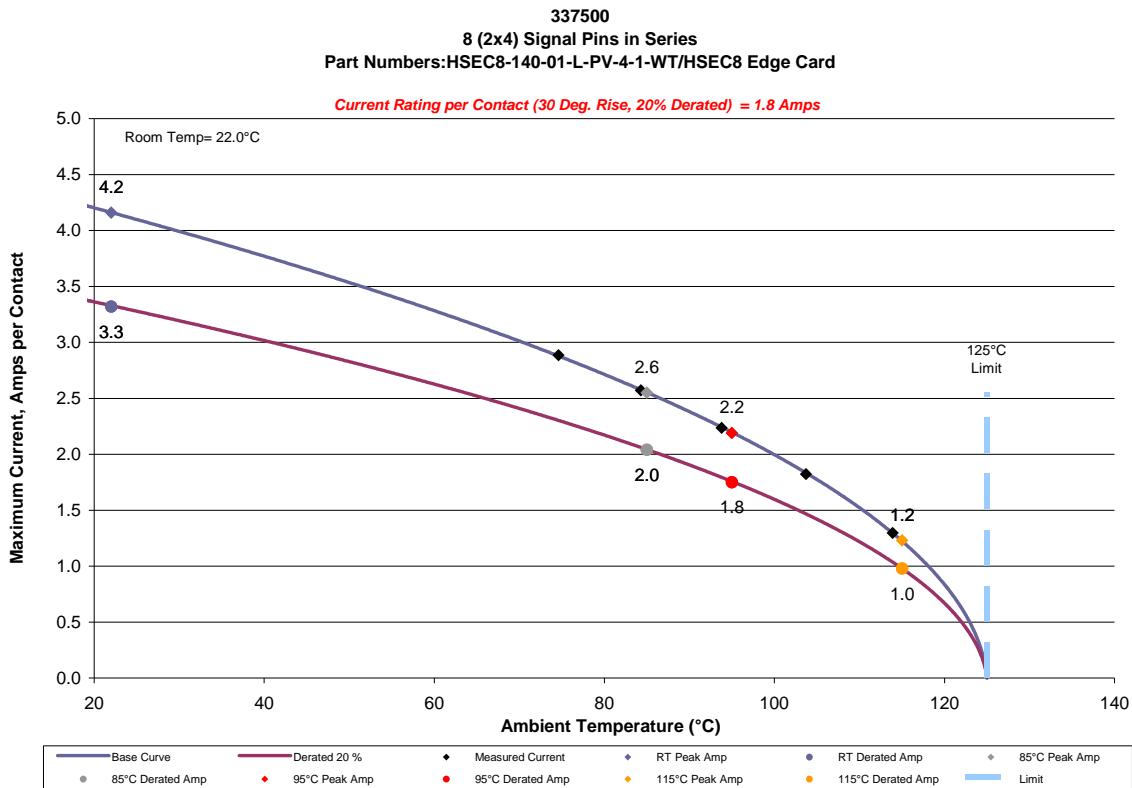
DATA SUMMARIES Continued

c. Linear configuration with 6 adjacent signal conductors/contacts powered



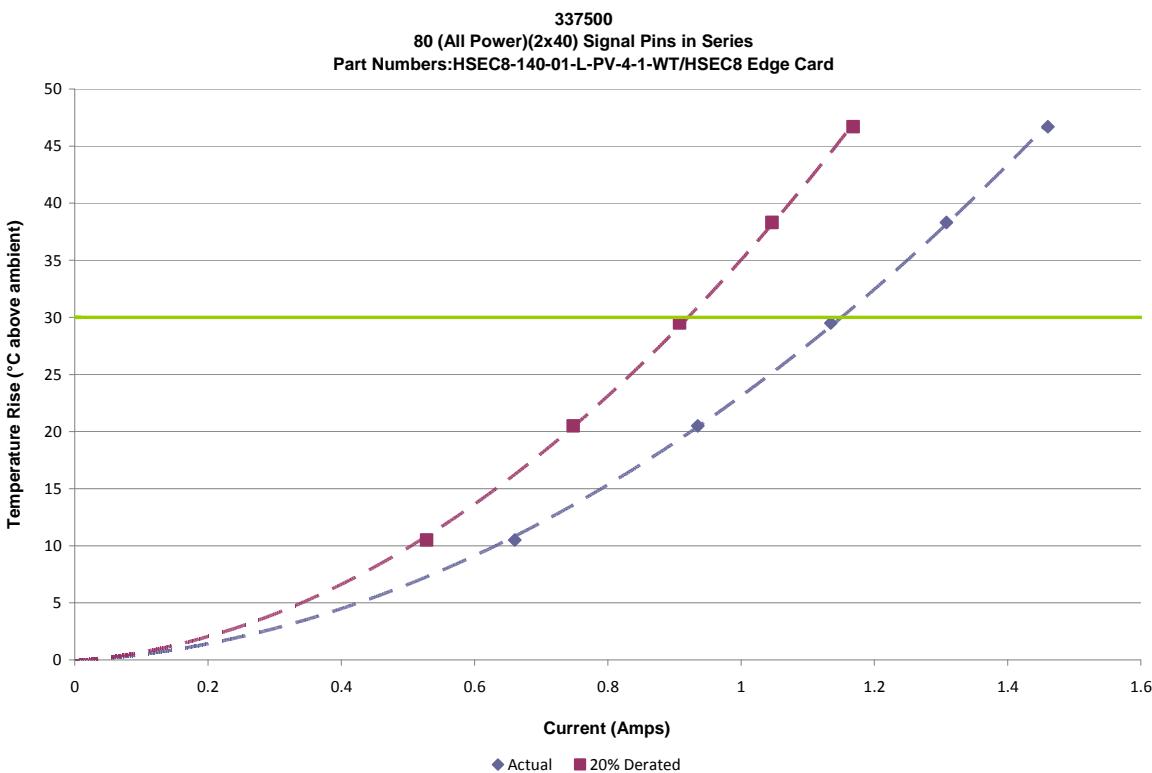
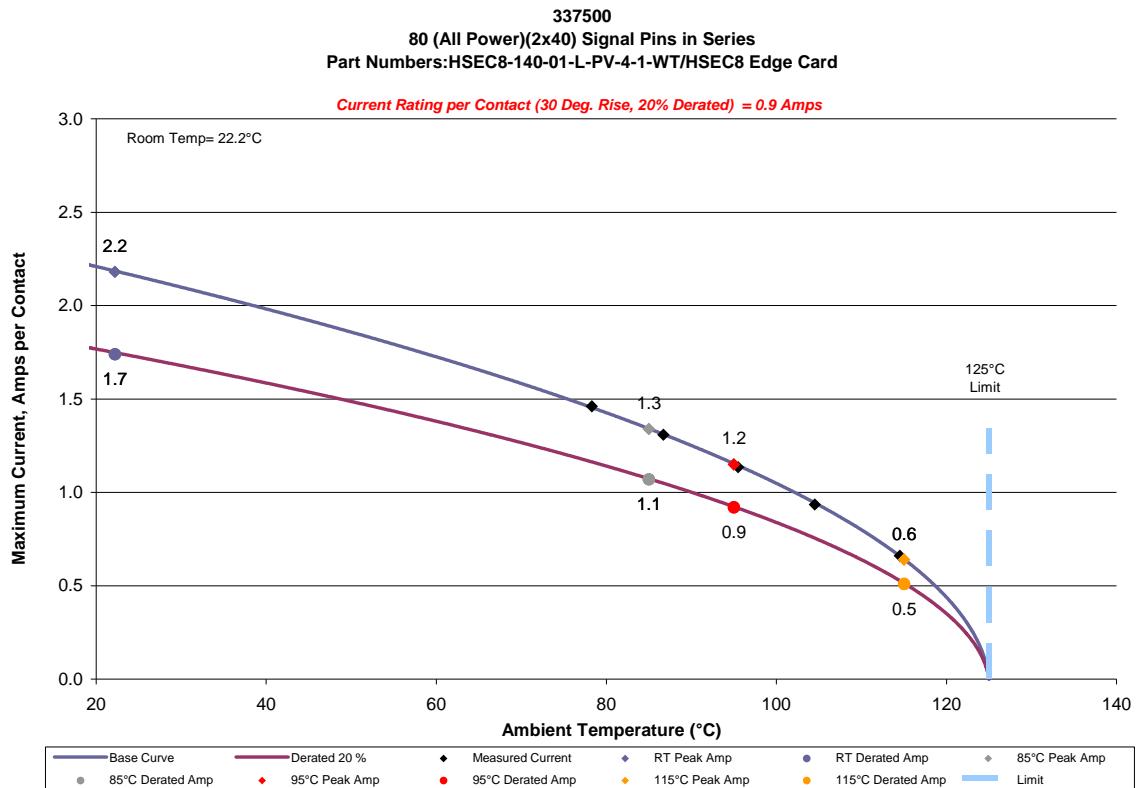
DATA SUMMARIES Continued

d. Linear configuration with 8 adjacent signal conductors/contacts powered



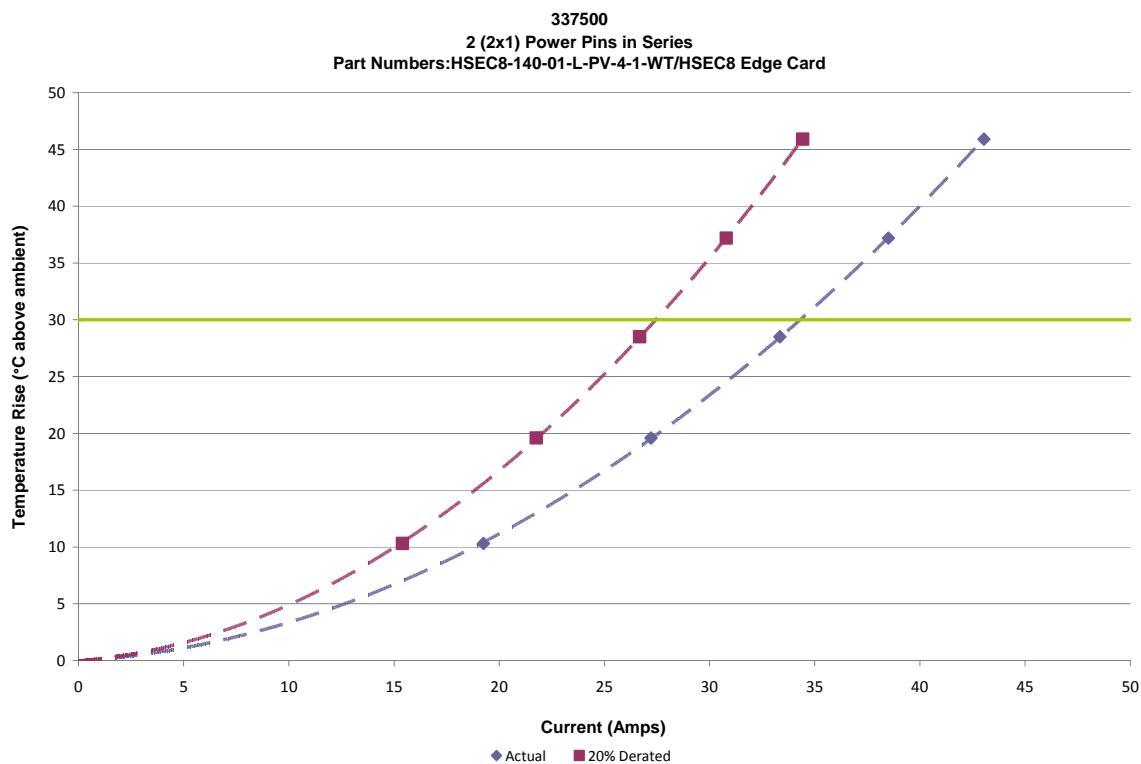
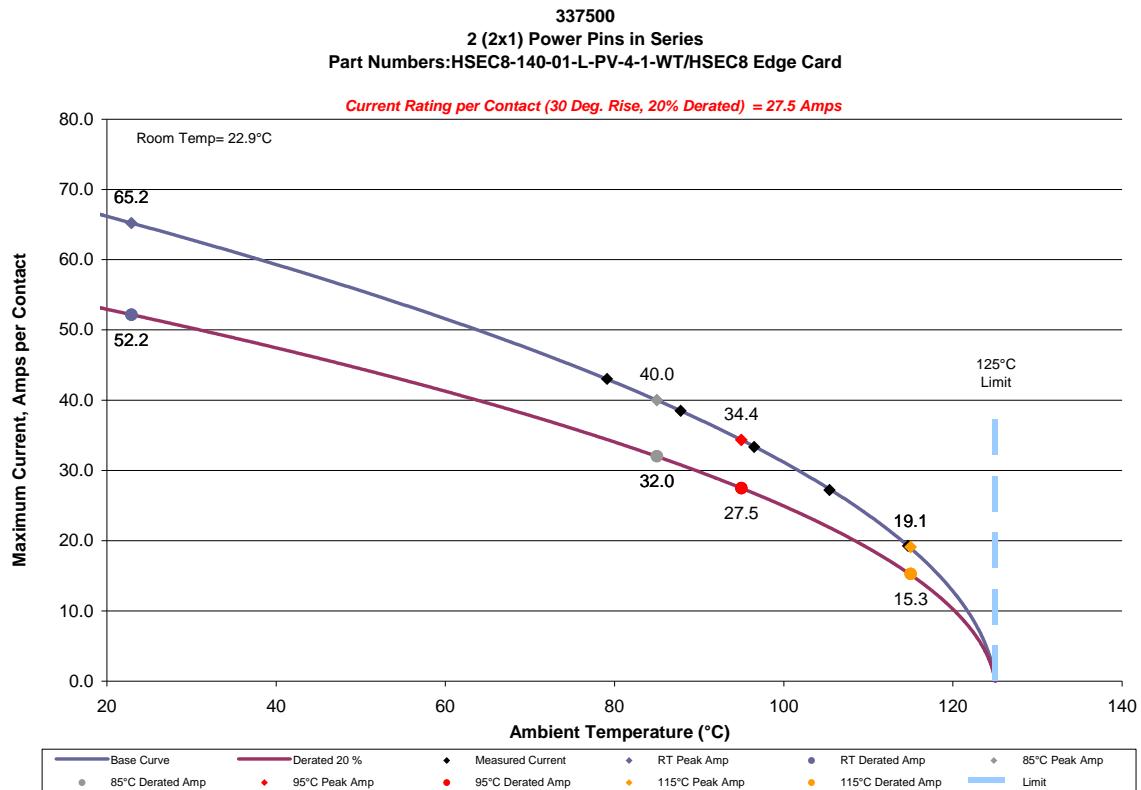
DATA SUMMARIES Continued

e. Linear configuration with all adjacent signal conductors/contacts powered



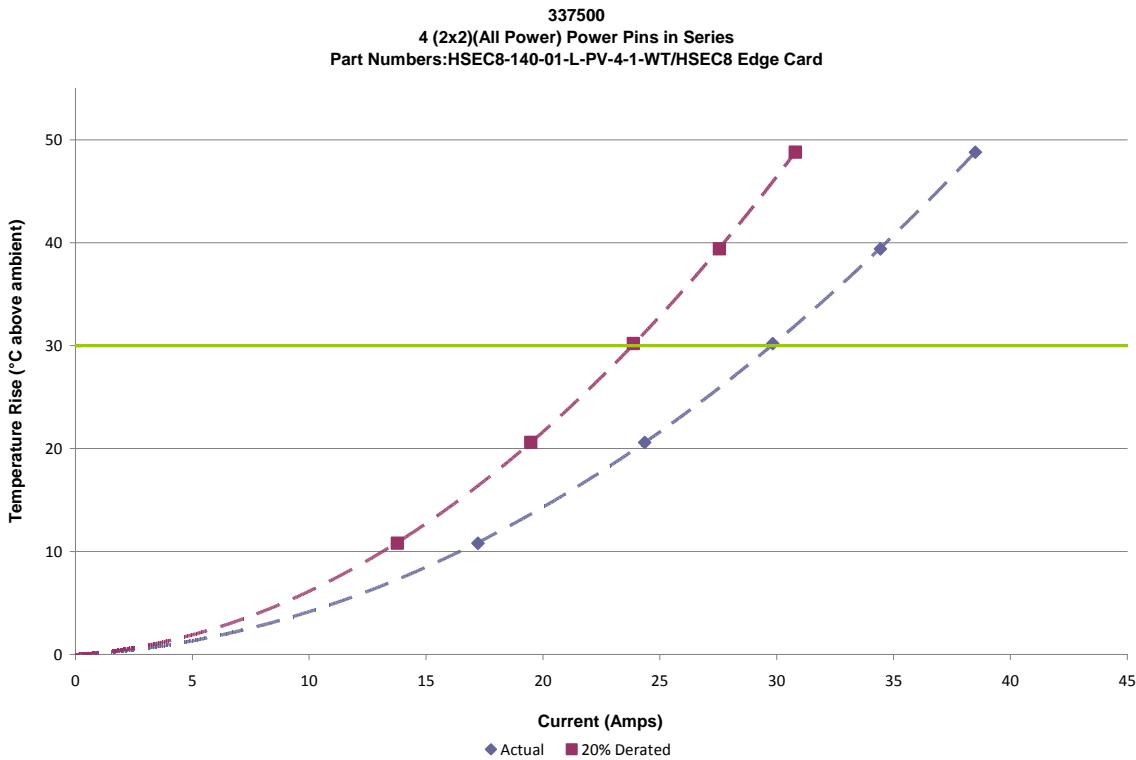
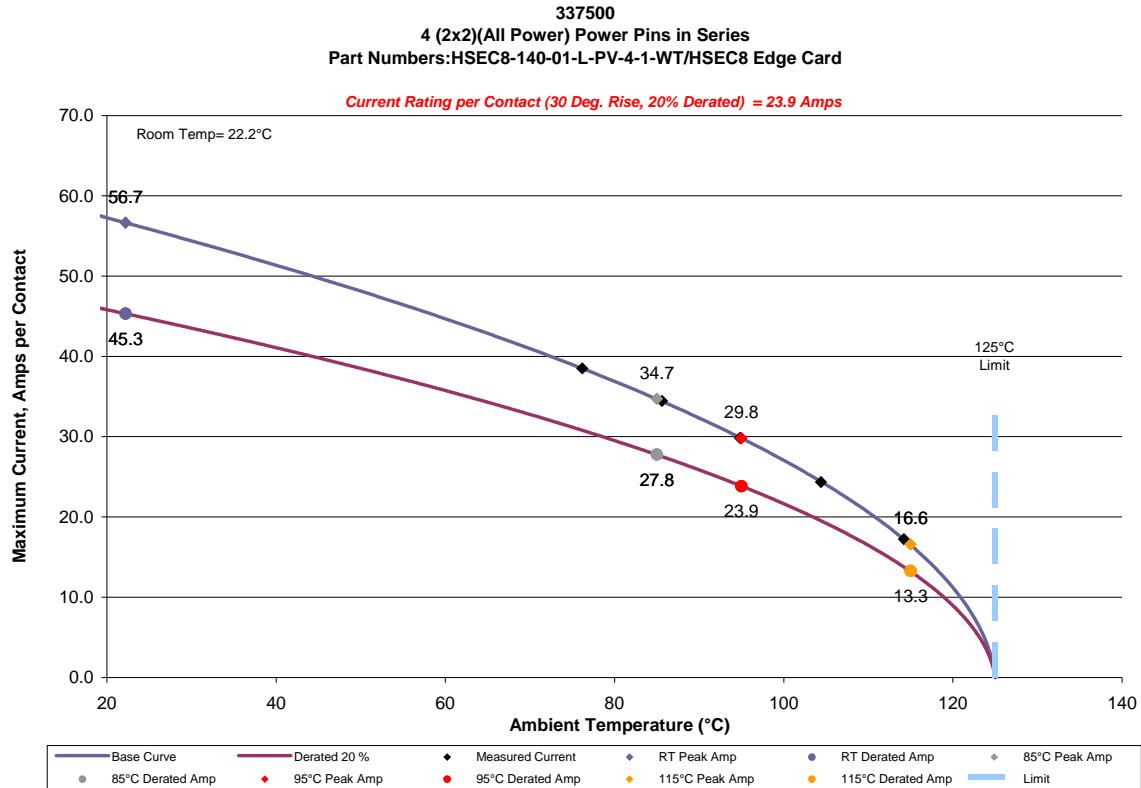
DATA SUMMARIES Continued

f. Linear configuration with 2 adjacent power conductors/contacts powered



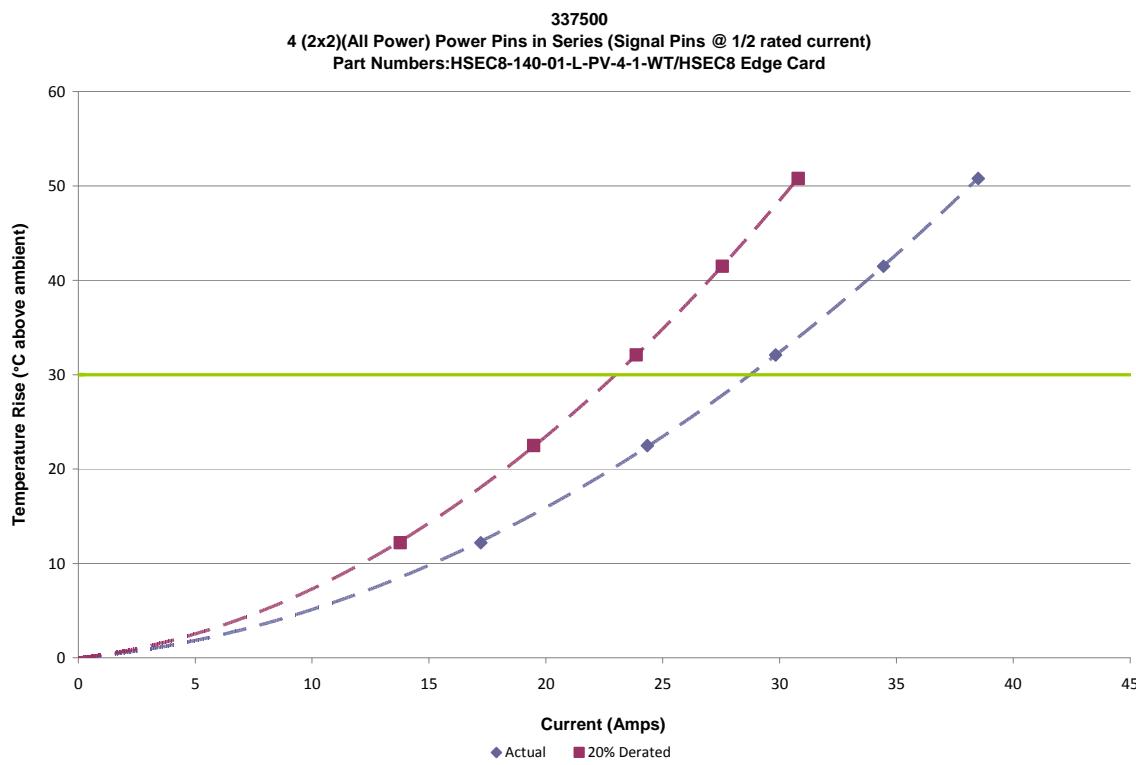
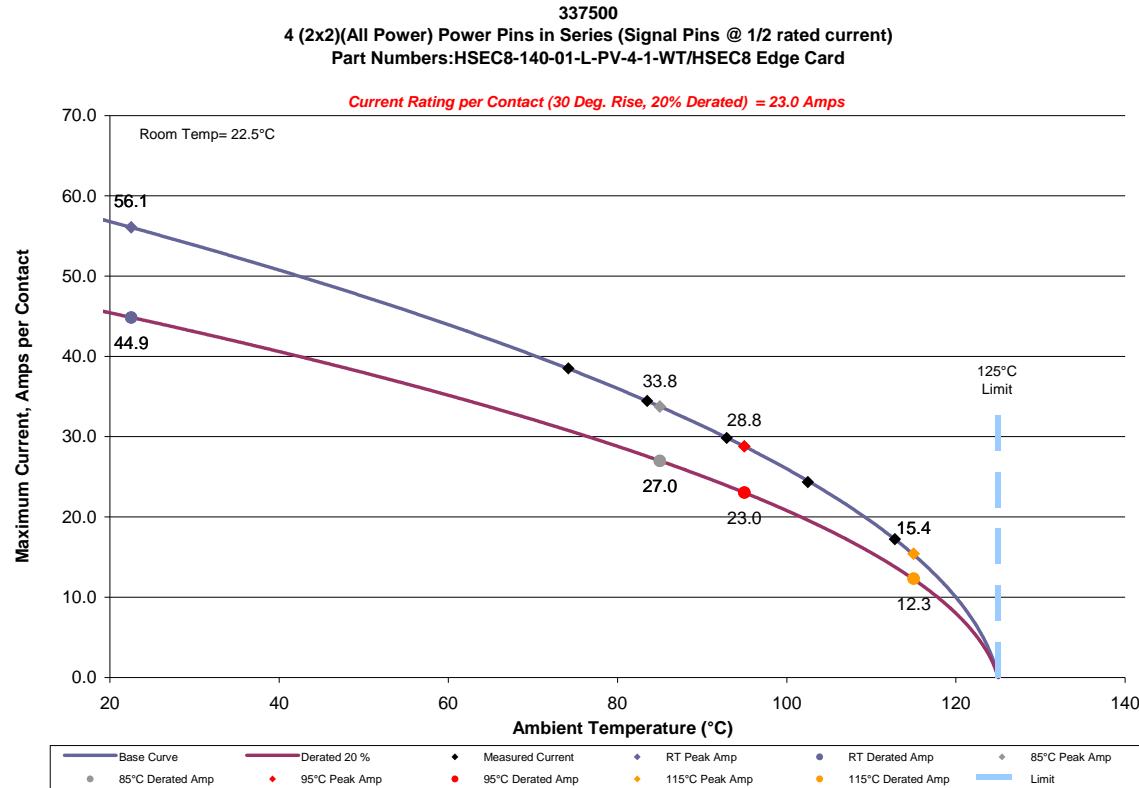
DATA SUMMARIES Continued

g. Linear configuration with 4 adjacent signal conductors/contacts powered



DATA SUMMARIES Continued

h. Linear configuration with all adjacent signal conductors and power conductors/contacts powered



DATA SUMMARIES Continued**MATING-UNMATING FORCE:**

Thermal Aging Group
Edge Card 0.056"

	Initial				After Thermals			
	Mating		Unmating		Mating		Unmating	
	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)
Minimum	35.58	8.00	20.10	4.52	30.11	6.77	19.35	4.35
Maximum	43.19	9.71	25.49	5.73	37.99	8.54	23.26	5.23
Average	39.25	8.83	24.10	5.42	34.74	7.81	21.34	4.80
St Dev	2.30	0.52	1.71	0.38	3.14	0.71	1.77	0.40
Count	8	8	8	8	8	8	8	8

Edge Card 0.068"

	Initial				After Thermals			
	Mating		Unmating		Mating		Unmating	
	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)
Minimum	49.55	11.14	27.53	6.19	36.03	8.10	20.37	4.58
Maximum	60.09	13.51	36.87	8.29	45.55	10.24	24.78	5.57
Average	55.47	12.47	31.02	6.97	41.99	9.44	21.85	4.91
St Dev	3.67	0.83	2.88	0.65	2.80	0.63	1.42	0.32
Count	8	8	8	8	8	8	8	8

DATA SUMMARIES Continued

MATING-UNMATING FORCE:

Mating-Unmating Durability Group (HSEC8-140-01-L-PV-4-1-WT/Edge Card 0.056")

	Initial				After 25 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)
Minimum	33.32	7.49	18.55	4.17	42.70	9.60	22.60	5.08
Maximum	40.70	9.15	21.39	4.81	51.64	11.61	26.73	6.01
Average	37.77	8.49	19.70	4.43	46.28	10.41	25.36	5.70
St Dev	2.28	0.51	1.03	0.23	2.95	0.66	1.36	0.31
Count	8	8	8	8	8	8	8	8
	After 50 Cycles				After 75 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)
Minimum	47.68	10.72	25.98	5.84	52.66	11.84	28.38	6.38
Maximum	54.71	12.30	28.87	6.49	56.85	12.78	32.07	7.21
Average	49.90	11.22	27.72	6.23	54.49	12.25	30.38	6.83
St Dev	2.12	0.48	1.08	0.24	1.53	0.34	1.31	0.29
Count	8	8	8	8	8	8	8	8
	After 100 Cycles				After Humidity			
	Mating		Unmating		Mating		Unmating	
	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)
Minimum	54.80	12.32	29.70	6.68	23.89	5.37	13.57	3.05
Maximum	62.01	13.94	34.87	7.84	37.01	8.32	24.06	5.41
Average	57.72	12.98	32.86	7.39	29.24	6.57	17.59	3.95
St Dev	2.36	0.53	1.67	0.38	5.28	1.19	3.95	0.89
Count	8	8	8	8	8	8	8	8

SUMMARIES Continued**MATING-UNMATING FORCE:****Mating-Unmating Durability Group (HSEC8-140-01-L-PV-4-1-WT/Edge Card 0.068")**

	Initial				After 25 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)
Minimum	42.48	9.55	20.95	4.71	50.89	11.44	25.98	5.84
Maximum	49.77	11.19	25.18	5.66	56.85	12.78	30.74	6.91
Average	46.23	10.39	22.91	5.15	52.88	11.89	28.29	6.36
St Dev	2.73	0.61	1.47	0.33	2.16	0.48	2.05	0.46
Count	8	8	8	8	8	8	8	8
	After 50 Cycles				After 75 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)
Minimum	54.98	12.36	30.87	6.94	58.89	13.24	33.36	7.50
Maximum	62.14	13.97	35.05	7.88	66.32	14.91	38.43	8.64
Average	58.77	13.21	32.45	7.30	62.79	14.12	35.78	8.04
St Dev	2.80	0.63	1.42	0.32	2.73	0.61	1.67	0.38
Count	8	8	8	8	8	8	8	8
	After 100 Cycles				After Humidity			
	Mating		Unmating		Mating		Unmating	
	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)
Minimum	63.03	14.17	33.94	7.63	31.45	7.07	18.77	4.22
Maximum	70.14	15.77	41.68	9.37	44.70	10.05	29.53	6.64
Average	66.59	14.97	38.68	8.70	36.74	8.26	21.81	4.90
St Dev	2.69	0.60	2.44	0.55	4.42	0.99	4.18	0.94
Count	8	8	8	8	8	8	8	8

DATA SUMMARIES Continued

MATING-UNMATING FORCE:

Mating-Unmating Basic (HSEC8-120-01-L-PV-2-1-WT/Edge Card 0.068")

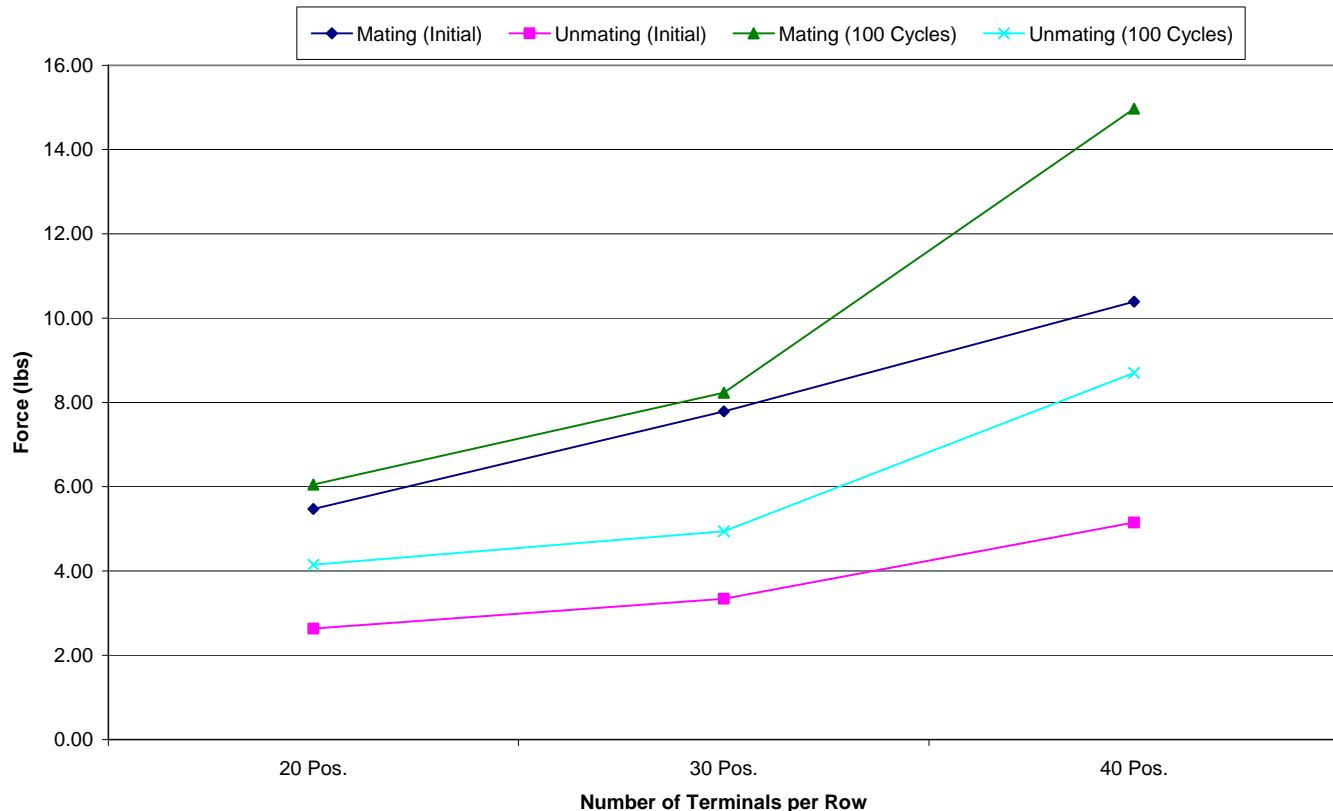
	Initial				After 25 Cycles				
	Mating		Unmating		Mating		Unmating		
	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)	
Minimum	22.73	5.11	10.63	2.39	22.37	5.03	12.59	2.83	
Maximum	25.53	5.74	12.59	2.83	27.98	6.29	16.55	3.72	
Average	24.33	5.47	11.69	2.63	25.93	5.83	15.50	3.48	
St Dev	1.10	0.25	0.58	0.13	1.72	0.39	1.29	0.29	
Count	8	8	8	8	8	8	8	8	
After 50 Cycles				After 75 Cycles					
Mating		Unmating		Mating		Unmating			
Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)		
Minimum	23.00	5.17	13.61	3.06	22.68	5.10	14.14	3.18	
Maximum	28.38	6.38	17.88	4.02	28.42	6.39	19.17	4.31	
Average	26.39	5.93	16.74	3.76	26.68	6.00	17.79	4.00	
St Dev	1.65	0.37	1.47	0.33	1.88	0.42	1.65	0.37	
Count	8	8	8	8	8	8	8	8	
After 100 Cycles									
Mating		Unmating							
Newton	Force (Lbs)	Newton	Force (Lbs)						
Minimum	22.68	5.10	14.14	3.18					
Maximum	28.78	6.47	20.15	4.53					
Average	26.89	6.05	18.46	4.15					
St Dev	1.98	0.45	1.96	0.44					
Count	8	8	8	8					

DATA SUMMARIES Continued

MATING-UNMATING FORCE:

Mating-Unmating Basic (HSEC8-130-01-L-PV-2-1-WT/Edge Card 0.068")

	Initial				After 25 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)
Minimum	32.03	7.20	14.14	3.18	33.32	7.49	16.15	3.63
Maximum	35.90	8.07	16.06	3.61	38.34	8.62	20.91	4.70
Average	34.64	7.79	14.83	3.34	35.97	8.09	19.09	4.29
St Dev	1.50	0.34	0.67	0.15	1.85	0.42	1.57	0.35
Count	8	8	8	8	8	8	8	8
	After 50 Cycles				After 75 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)
Minimum	33.80	7.60	17.61	3.96	34.03	7.65	18.28	4.11
Maximum	38.56	8.67	22.73	5.11	38.65	8.69	23.17	5.21
Average	36.46	8.20	20.43	4.59	36.56	8.22	21.31	4.79
St Dev	1.58	0.36	1.70	0.38	1.39	0.31	1.72	0.39
Count	8	8	8	8	8	8	8	8
	After 100 Cycles							
	Mating		Unmating					
	Newton	Force (Lbs)	Newton	Force (Lbs)				
Minimum	34.21	7.69	18.64	4.19				
Maximum	38.74	8.71	24.11	5.42				
Average	36.60	8.23	21.95	4.94				
St Dev	1.52	0.34	1.81	0.41				
Count	8	8	8	8				

DATA SUMMARIES Continued**Mating\Unmating Force Comparison****Mating/Unmating Data for 20, 30 and 40 Position HSEC8/Card**

DATA SUMMARIES Continued

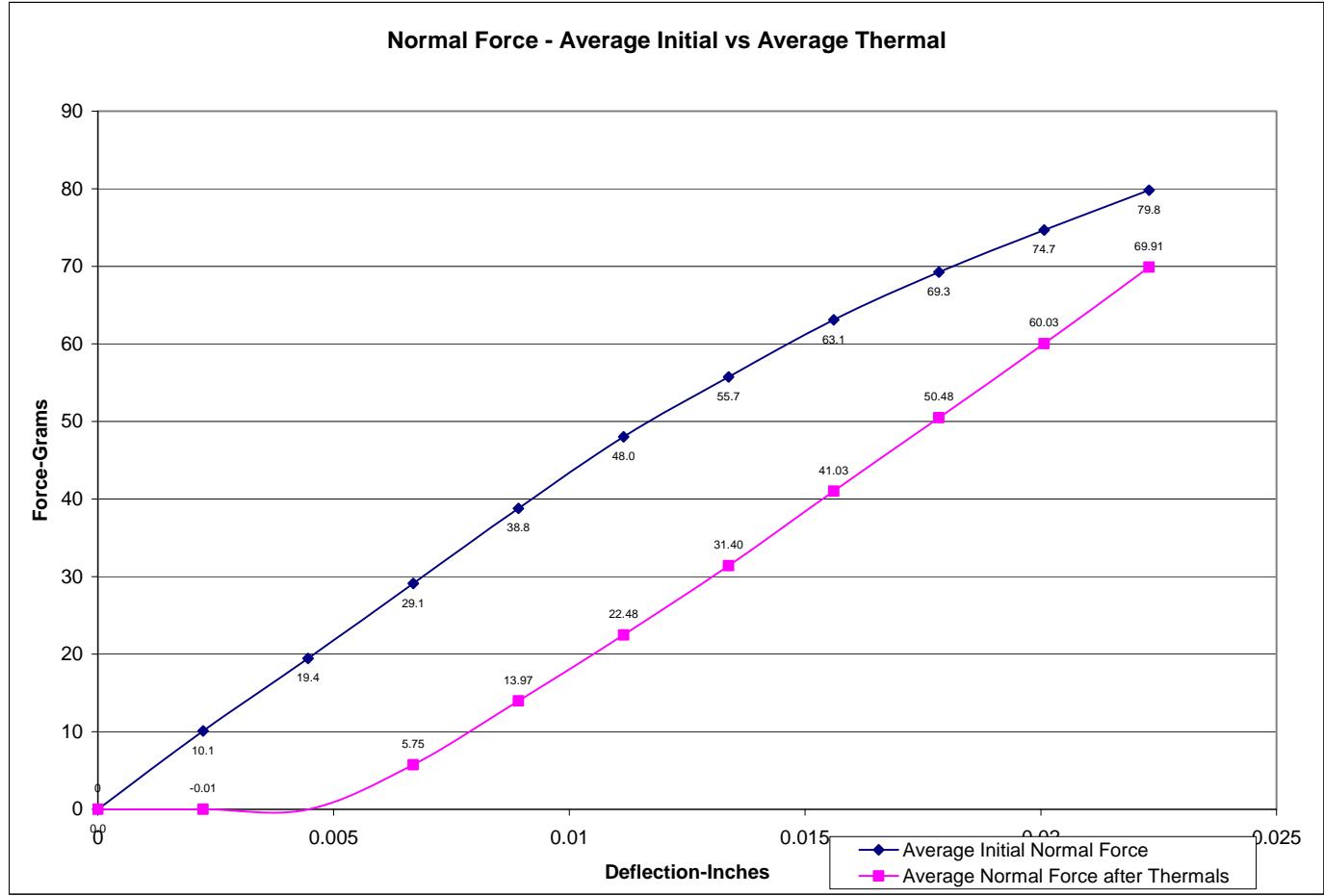
NORMAL FORCE (FOR CONTACTS TESTED IN THE HOUSING):

- 1) Calibrated force gauges are used along with computer controlled positioning equipment.
- 2) For Normal force 8-10 measurements are taken and the averages reported.

C-188-02 Signal pin

Initial	Deflections in inches Forces in Grams										
	0.0022	0.0045	0.0067	0.0089	0.0112	0.0134	0.0156	0.0178	0.0201	0.0223	SET
Averages	10.09	19.44	29.13	38.78	48.02	55.74	63.10	69.27	74.68	79.81	0.0048
Min	9.50	18.50	27.30	36.90	46.10	53.70	61.50	67.10	72.40	78.00	0.0045
Max	10.70	20.50	30.70	40.40	50.00	58.20	65.50	72.30	77.50	82.20	0.0051
St. Dev	0.378	0.619	0.966	0.981	1.094	1.235	1.180	1.458	1.466	1.368	0.0002
Count	12	12	12	12	12	12	12	12	12	12	12

After Thermals	Deflections in inches Forces in Grams										
	0.0022	0.0045	0.0067	0.0089	0.0112	0.0134	0.0156	0.0178	0.0201	0.0223	SET
Averages	-0.01	-0.02	5.75	13.97	22.48	31.40	41.03	50.48	60.03	69.91	0.0054
Min	-0.20	-0.20	5.30	13.20	21.00	29.90	39.00	48.30	57.60	67.70	0.0050
Max	0.10	0.10	6.70	15.80	25.10	34.80	45.20	54.90	63.90	74.30	0.0057
St. Dev	0.108	0.103	0.412	0.692	1.066	1.219	1.647	1.705	1.737	1.705	0.0002
Count	12	12	12	12	12	12	12	12	12	12	12



DATA SUMMARIES Continued

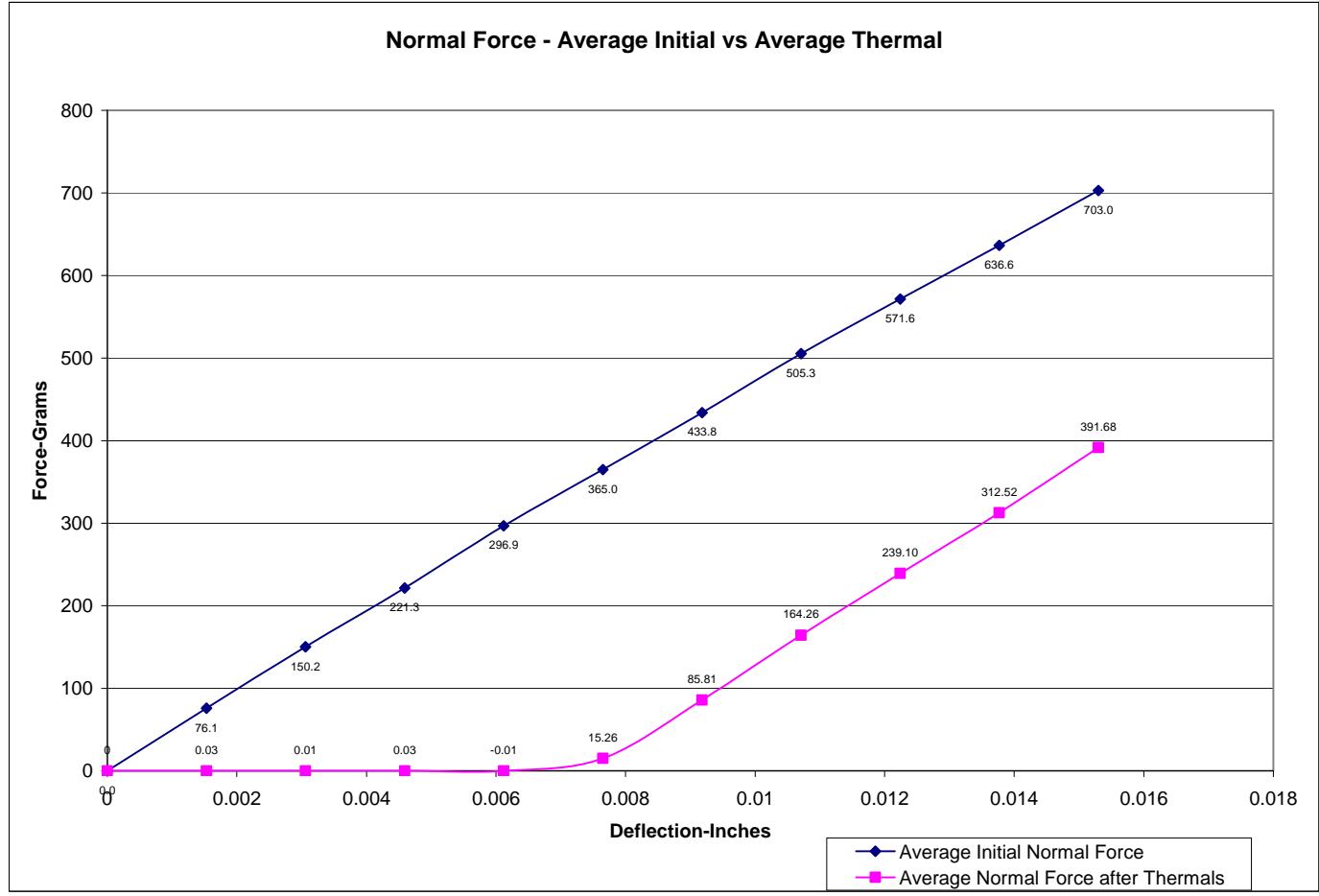
NORMAL FORCE (FOR CONTACTS TESTED IN THE HOUSING):

- 1) Calibrated force gauges are used along with computer controlled positioning equipment.
- 2) For Normal force 8-10 measurements are taken and the averages reported.

C-367-02 Power pin - left

	Deflections in inches Forces in Grams										
	Initial	0.0015	0.0031	0.0046	0.0061	0.0077	0.0092	0.0107	0.0122	0.0138	0.0153
Averages	76.05	150.22	221.33	296.88	365.03	433.78	505.31	571.58	636.56	702.98	0.0007
Min	70.80	138.90	207.60	275.60	344.40	410.00	480.10	545.50	604.80	668.70	0.0003
Max	79.60	160.50	233.30	310.60	378.20	450.10	520.20	587.20	662.20	735.60	0.0010
St. Dev	2.636	6.674	9.294	10.366	10.037	11.171	12.016	12.367	15.978	18.318	0.0002
Count	12	12	12	12	12	12	12	12	12	12	12

After Thermals	Deflections in inches Forces in Grams										
	0.0015	0.0031	0.0046	0.0061	0.0077	0.0092	0.0107	0.0122	0.0138	0.0153	SET
Averages	0.03	0.01	0.03	-0.01	15.26	85.81	164.26	239.10	312.52	391.68	0.0076
Min	-0.40	-0.40	-0.40	-0.40	-0.40	54.50	134.40	206.40	274.40	351.50	0.0068
Max	0.50	0.50	0.50	0.50	48.10	118.70	200.80	285.10	365.60	450.10	0.0082
St. Dev	0.260	0.268	0.264	0.271	17.289	23.479	24.338	28.530	31.242	34.856	0.0004
Count	12	12	12	12	12	12	12	12	12	12	12



DATA SUMMARIES Continued

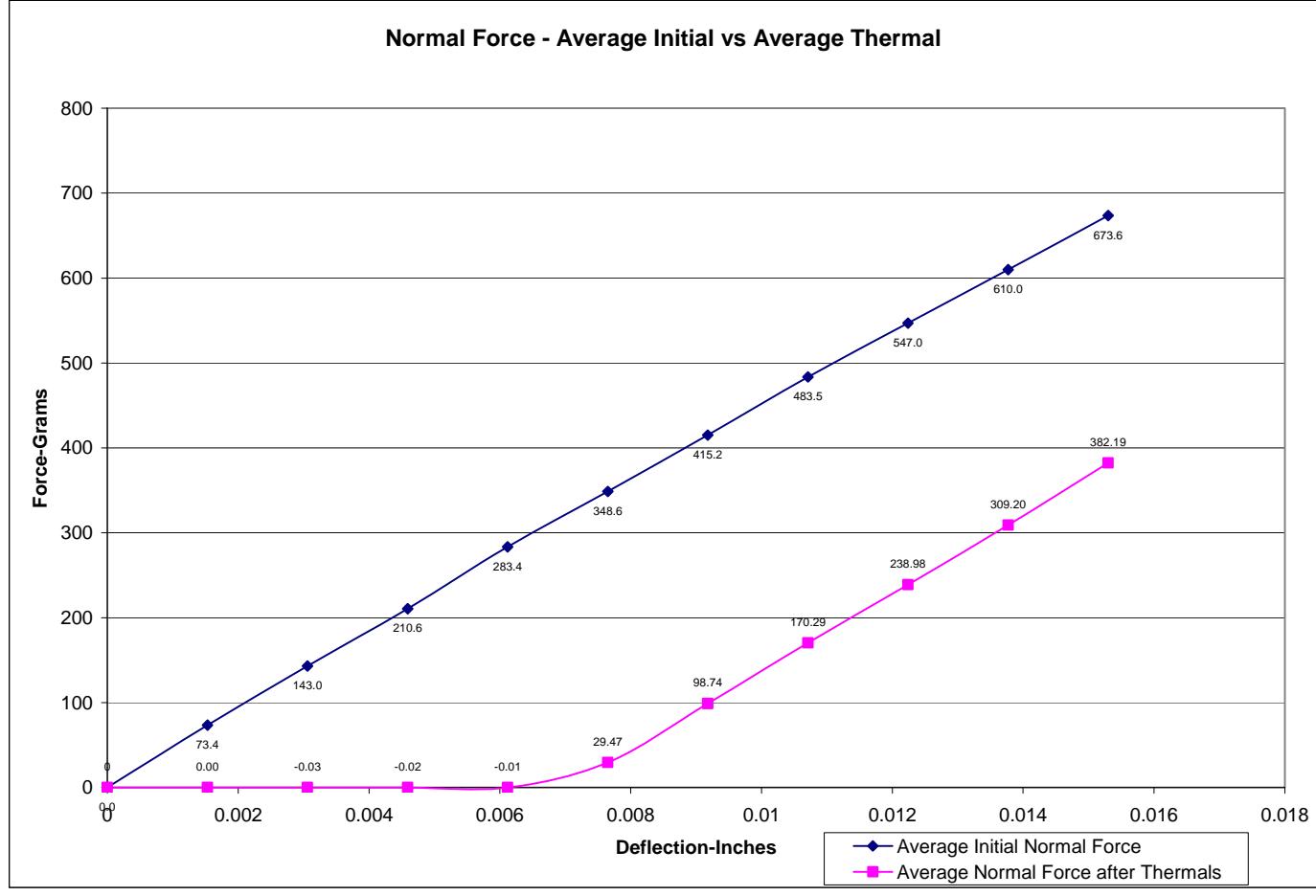
NORMAL FORCE (FOR CONTACTS TESTED IN THE HOUSING):

- 1) Calibrated force gauges are used along with computer controlled positioning equipment.
- 2) For Normal force 8-10 measurements are taken and the averages reported.

C-367-02 Power pin - middle

	Deflections in inches Forces in Grams										
	Initial	0.0015	0.0031	0.0046	0.0061	0.0077	0.0092	0.0107	0.0122	0.0138	0.0153
Averages	73.38	142.98	210.61	283.38	348.55	415.15	483.46	547.00	609.96	673.62	0.0005
Min	61.00	126.20	188.00	252.10	313.90	376.40	446.10	504.40	565.80	617.90	0.0002
Max	82.20	157.10	230.10	308.30	378.10	450.30	524.30	589.70	656.80	705.50	0.0008
St. Dev	6.089	9.476	11.954	15.694	17.103	19.399	20.482	21.855	23.105	23.328	0.0002
Count	12	12	12	12	12	12	12	12	12	12	12

After Thermals	Deflections in inches Forces in Grams										
	0.0015	0.0031	0.0046	0.0061	0.0077	0.0092	0.0107	0.0122	0.0138	0.0153	SET
Averages	0.00	-0.03	-0.02	-0.01	29.47	98.74	170.29	238.98	309.20	382.19	0.0072
Min	-0.40	-0.50	-0.50	-0.50	0.10	68.80	144.30	208.40	279.40	348.20	0.0068
Max	0.40	0.40	0.40	0.40	49.10	120.50	200.40	274.10	350.40	429.90	0.0078
St. Dev	0.252	0.245	0.266	0.275	14.195	14.001	15.796	17.252	18.819	21.139	0.0003
Count	12	12	12	12	12	12	12	12	12	12	12



DATA SUMMARIES Continued

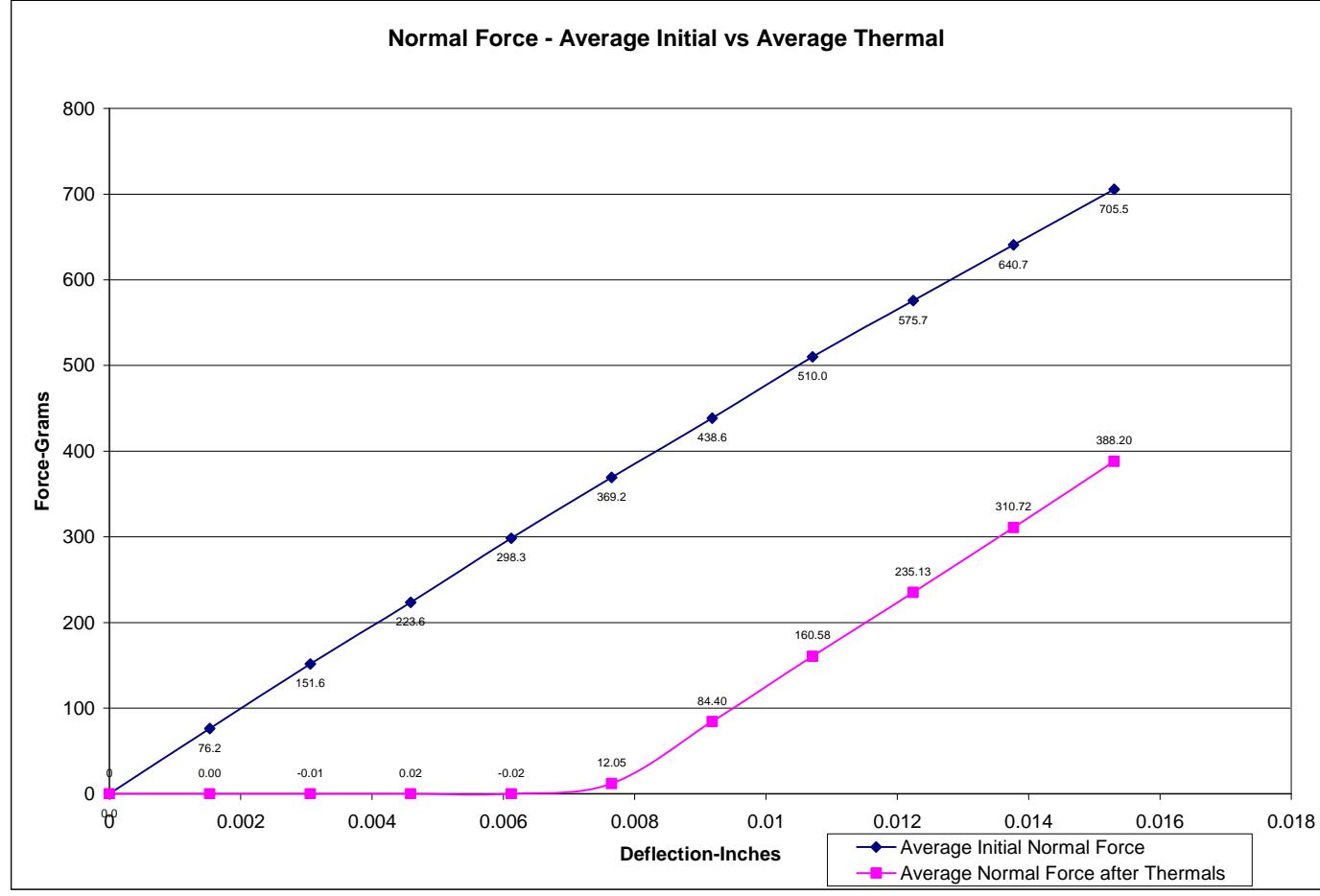
NORMAL FORCE (FOR CONTACTS TESTED IN THE HOUSING):

- 1) Calibrated force gauges are used along with computer controlled positioning equipment.
- 2) For Normal force 8-10 measurements are taken and the averages reported.

C-367-02 Power pin - right

	Deflections in inches Forces in Grams										
	Initial	0.0015	0.0031	0.0046	0.0061	0.0077	0.0092	0.0107	0.0122	0.0138	0.0153
Averages	76.23	151.60	223.56	298.26	369.24	438.58	510.00	575.65	640.73	705.53	0.0006
Min	62.90	138.50	208.10	274.00	335.20	399.00	463.90	525.00	584.00	644.90	0.0002
Max	91.40	162.60	239.40	317.20	392.50	465.70	535.70	603.70	668.40	733.00	0.0008
St. Dev	7.634	8.932	11.384	13.942	17.195	18.106	19.186	20.599	21.175	21.998	0.0002
Count	12	12	12	12	12	12	12	12	12	12	12

After Thermals	Deflections in inches Forces in Grams										
	0.0015	0.0031	0.0046	0.0061	0.0077	0.0092	0.0107	0.0122	0.0138	0.0153	SET
Averages	0.00	-0.01	0.02	-0.02	12.05	84.40	160.58	235.13	310.72	388.20	0.0076
Min	-0.30	-0.40	-0.30	-0.30	0.10	57.70	133.90	208.10	282.90	360.80	0.0073
Max	0.20	0.20	0.30	0.20	27.80	99.30	175.60	250.90	328.10	406.90	0.0081
St. Dev	0.176	0.178	0.175	0.180	9.435	11.840	11.609	12.027	12.900	12.937	0.0002
Count	12	12	12	12	12	12	12	12	12	12	12



DATA SUMMARIES Continued

INSULATION RESISTANCE (IR):

Pin to Pin (Signal)			
	Mated	Unmated	Unmated
Minimum	HSEC8/Card	HSEC8	Card
Initial	10000	10000	Not Tested
Thermal	10000	10000	Not Tested
Humidity	10000	10000	Not Tested

Row to Row (Signal)			
	Mated	Unmated	Unmated
Minimum	HSEC8/Card	HSEC8	Card
Initial	10000	10000	Not Tested
Thermal	10000	10000	Not Tested
Humidity	10000	10000	Not Tested

Pin to Pin (Power)			
	Mated	Unmated	Unmated
Minimum	HSEC8/Card	HSEC8	Card
Initial	10000	10000	Not Tested
Thermal	10000	10000	Not Tested
Humidity	10000	10000	Not Tested

Row to Row (Power)			
	Mated	Unmated	Unmated
Minimum	HSEC8/Card	HSEC8	Card
Initial	10000	10000	Not Tested
Thermal	10000	10000	Not Tested
Humidity	10000	10000	Not Tested

Signal to Power			
	Mated	Unmated	Unmated
Minimum	HSEC8/Card	HSEC8	Card
Initial	10000	10000	Not Tested
Thermal	10000	10000	Not Tested
Humidity	10000	10000	Not Tested

DIELECTRIC WITHSTANDING VOLTAGE (DWV):

Voltage Rating Summary	
Minimum	HSEC8/Card
Break Down Voltage	875
Test Voltage	660
Working Voltage	215

Pin to Pin (Signal)	
Initial Test Voltage	Passed
After Thermal Test Voltage	Passed
After Humidity Test Voltage	Passed

Row to Row (Signal)	
Initial Test Voltage	Passed
After Thermal Test Voltage	Passed
After Humidity Test Voltage	Passed

Pin to Pin (Power)	
Initial Test Voltage	Passed
After Thermal Test Voltage	Passed
After Humidity Test Voltage	Passed

Row to Row (Power)	
Initial Test Voltage	Passed
After Thermal Test Voltage	Passed
After Humidity Test Voltage	Passed

Signal to Power	
Initial Test Voltage	Passed
After Thermal Test Voltage	Passed
After Humidity Test Voltage	Passed

DATA SUMMARIES Continued

LLCR Thermal Aging Group

- 1) A total of 192 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: -----Stable
 - b. $+5.1$ to $+10.0$ mOhms: -----Minor
 - c. $+10.1$ to $+15.0$ mOhms: -----Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: -----Marginal
 - e. $+50.1$ to $+2000$ mOhms: -----Unstable
 - f. $>+2000$ mOhms: -----Open Failure

Edge Card 0.056"

		LLCR Measurement Summaries by Pin Type			
Date		6/4/2014	6/19/2014		
		23	23		
Room Temp (Deg C)		59	53		
Rel Humidity (%)		Kason He	Kason He		
Technician		Actual	Delta	Delta	Delta
		Initial	Thermal		
Pin Type 1: Signal					
mOhm values		6.36	1.69		
		0.48	1.18		
Average		5.46	0.03		
		7.83	6.14		
St. Dev.		160	160		
		160	160		
Min					
Max					
Summary Count					
Total Count					
Pin Type 2: Power					
mOhm values		0.24	0.05		
		0.01	0.03		
Average		0.20	0.00		
		0.28	0.09		
St. Dev.		32	32		
		32	32		
Min					
Max					
Summary Count					
Total Count					

LLCR Delta Count by Category						
mOhms	Stable	Minor	Acceptable	Marginal	Unstable	Open
	≤ 5	$>5 \text{ & } \leq 10$	$>10 \text{ & } \leq 15$	$>15 \text{ & } \leq 50$	$>50 \text{ & } \leq 1000$	>1000
Thermal	187	5	0	0	0	0

Edge Card 0.068"

LLCR Measurement Summaries by Pin Type						
mOhm values	Date	6/4/2014	6/19/2014			
	Room Temp (Deg C)	23	23			
	Rel Humidity (%)	59	53			
	Technician	Kason He	Kason He			
	Actual Initial	Delta Thermal	Delta	Delta		
	Pin Type 1: Signal					
Average	5.96	1.05				
St. Dev.	0.52	0.70				
Min	5.13	0.01				
Max	7.81	4.28				
Summary Count	160	160				
Total Count	160	160				
Pin Type 2: Power						
Average	0.22	0.05				
St. Dev.	0.01	0.02				
Min	0.20	0.01				
Max	0.26	0.10				
Summary Count	32	32				
Total Count	32	32				

LLCR Delta Count by Category						
mOhms	Stable	Minor	Acceptable	Marginal	Unstable	Open
	<=5	>5 & <=10	>10 & <=15	>15 & <=50	>50 & <=1000	>1000
Thermal	192	0	0	0	0	0

DATA SUMMARIES Continued

LLCR Mating/Unmating Durability Group

- 1). A total of 192 points were measured.
- 2). EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3). A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4). The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: -----Stable
 - b. $+5.1$ to $+10.0$ mOhms: -----Minor
 - c. $+10.1$ to $+15.0$ mOhms: -----Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: -----Marginal
 - e. $+50.1$ to $+2000$ mOhms: -----Unstable
 - f. $> +2000$ mOhms: -----Open Failure

Edge Card 0.056"

		LLCR Measurement Summaries by Pin Type			
Date		7/25/2014	7/29/2014	8/4/2014	8/20/2014
Room Temp (Deg C)		24	24	24	24
Rel Humidity (%)		50	50	51	53
Technician	Kason He	Kason He	Kason He	Kason He	Kason He
mOhm values	Actual Initial	Delta 100 Cycles	Delta Therm Shck	Delta Humidity	
Pin Type 1: Signal					
Average	6.87	0.83	0.90	2.00	
St. Dev.	0.79	0.78	0.68	1.78	
Min	5.57	0.01	0.01	0.02	
Max	8.98	3.19	2.73	7.64	
Summary Count	160	160	160	160	
Total Count	160	160	160	160	
Pin Type 2: Power					
Average	0.24	0.02	0.08	0.10	
St. Dev.	0.02	0.02	0.05	0.10	
Min	0.19	0.00	0.00	0.01	
Max	0.30	0.09	0.24	0.48	
Summary Count	32	32	32	32	
Total Count	32	32	32	32	

LLCR Delta Count by Category						
mOhms	Stable	Minor	Acceptable	Marginal	Unstable	Open
	≤ 5	$>5 \text{ & } \leq 10$	$>10 \text{ & } \leq 15$	$>15 \text{ & } \leq 50$	$>50 \text{ & } \leq 1000$	>1000
100 Cycles	192	0	0	0	0	0
Therm Shck	192	0	0	0	0	0
Humidity	178	14	0	0	0	0

Edge Card 0.068"

		LLCR Measurement Summaries by Pin Type			
Technician	Date	7/25/2014	7/29/2014	8/4/2014	8/20/2014
		Room Temp (Deg C)	24	24	24
mOhm values	Rel Humidity (%)	50	50	51	53
	Kason He	Kason He	Kason He	Kason He	Kason He
Actual		Delta	Delta	Delta	Delta
Initial		100 Cycles	Therm Shck	Therm Shck	Humidity
Pin Type 1: Signal					
Average	6.98	1.06	0.94	1.96	
St. Dev.	0.91	0.82	0.78	1.77	
Min	5.15	0.01	0.01	0.00	
Max	10.00	3.84	3.14	7.65	
Summary Count	160	160	160	160	
Total Count	160	160	160	160	
Pin Type 2: Power					
Average	0.22	0.04	0.07	0.16	
St. Dev.	0.02	0.02	0.03	0.11	
Min	0.20	0.00	0.01	0.01	
Max	0.27	0.08	0.13	0.40	
Summary Count	32	32	32	32	
Total Count	32	32	32	32	

LLCR Delta Count by Category						
mOhms	Stable	Minor	Acceptable	Marginal	Unstable	Open
	<=5	>5 & <=10	>10 & <=15	>15 & <=50	>50 & <=1000	>1000
100 Cycles	192	0	0	0	0	0
Therm Shck	192	0	0	0	0	0
Humidity	179	13	0	0	0	0

DATA SUMMARIES Continued

LLCR Gas Tight Group

- 1) A total of 192 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: -----Stable
 - b. $+5.1$ to $+10.0$ mOhms: -----Minor
 - c. $+10.1$ to $+15.0$ mOhms: -----Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: -----Marginal
 - e. $+50.1$ to $+2000$ mOhms: -----Unstable
 - f. $>+2000$ mOhms: -----Open Failure

Edge Card 0.056"

		LLCR Measurement Summaries by Pin Type			
		5/29/2014	7/10/2014		
Room Temp (Deg C)		24	24		
Rel Humidity (%)		54	50		
Technician		Kason He	Kason He		
mOhm values	Actual	Delta	Delta	Delta	
	Initial	Acid Vapor			
Pin Type 1: Signal					
Average	7.07	0.71			
	0.76	0.59			
	5.58	0.00			
	9.20	3.32			
Summary Count	160	160			
	160	160			
Pin Type 2: Ground					
Average	0.25	0.02			
	0.02	0.02			
	0.19	0.00			
	0.30	0.09			
Summary Count	32	32			
	32	32			

LLCR Delta Count by Category						
mOhms	Stable	Minor	Acceptable	Marginal	Unstable	Open
	≤ 5	$>5 \text{ & } \leq 10$	$>10 \text{ & } \leq 15$	$>15 \text{ & } \leq 50$	$>50 \text{ & } \leq 1000$	>1000
Acid Vapor	192	0	0	0	0	0

DATA SUMMARIES Continued

LLCR Shock & Vibration Group

- 1) A total of 192 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: -----Stable
 - b. $+5.1$ to $+10.0$ mOhms: -----Minor
 - c. $+10.1$ to $+15.0$ mOhms: -----Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: -----Marginal
 - e. $+50.1$ to $+2000$ mOhms: -----Unstable
 - f. $>+2000$ mOhms: -----Open Failure

Edge Card 0.056"

LLCR Measurement Summaries by Pin Type						
	Date		7/3/2014		7/8/2014	
	Room Temp (Deg C)	Rel Humidity (%)	22	40	22	40
Technician	Tony Wagoner	Tony Wagoner				
mOhm values	Actual Initial		Delta Shock-Vib		Delta	Delta
Pin Type 1: Signal						
Average	6.62		0.63			
St. Dev.	0.59		0.46			
Min	5.64		0.00			
Max	9.81		3.30			
Summary Count	160		160			
Total Count	160		160			
Pin Type 2: Power						
Average	0.26		0.02			
St. Dev.	0.03		0.02			
Min	0.22		0.00			
Max	0.37		0.09			
Summary Count	32		32			
Total Count	32		32			

LLCR Delta Count by Category						
mOhms	Stable	Minor	Acceptable	Marginal	Unstable	Open
	≤ 5	$>5 \text{ & } \leq 10$	$>10 \text{ & } \leq 15$	$>15 \text{ & } \leq 50$	$>50 \text{ & } \leq 1000$	>1000
Shock-Vib	192	0	0	0	0	0

Nanosecond Event Detection:

Shock and Vibration Event Detection Summary	
Contacts tested	60
Test Condition	C, 100g's, 6ms, Half-Sine
Shock Events	0
Test Condition	V-B, 7.56 rms g
Vibration Events	0
Total Events	0

Edge Card 0.068"

		LLCR Measurement Summaries by Pin Type			
mOhm values	Date	7/3/2014	7/9/2014	Delta	Delta
	Room Temp (Deg C)	22	23		
	Rel Humidity (%)	39	39		
	Technician	Tony Wagoner	Tony Wagoner		
	Actual		Delta	Delta	Delta
	Initial		Shock-Vib		
	Pin Type 1: Signal				
	Average	6.40	0.72		
	St. Dev.	0.50	0.44		
	Min	5.48	0.02		
	Max	8.31	2.21		
	Summary Count	160	160		
	Total Count	160	160		
Pin Type 2: Power					
Average	0.23	0.02			
St. Dev.	0.02	0.02			
Min	0.21	0.00			
Max	0.33	0.11			
Summary Count	32	32			
Total Count	32	32			

LLCR Delta Count by Category						
mOhms	Stable	Minor	Acceptable	Marginal	Unstable	Open
	<=5	>5 & <=10	>10 & <=15	>15 & <=50	>50 & <=1000	>1000
Shock-Vib	192	0	0	0	0	0

EQUIPMENT AND CALIBRATION SCHEDULES

Equipment #: HZ-TCT-01

Description: Normal force analyzer

Manufacturer: Mecmesin Multitester

Model: Mecmesin Multitester 2.5-i

Serial #: 08-1049-04

Accuracy: Last Cal: 4/25/2014, Next Cal: 4/24/2015

Equipment #: HZ-OV-01

Description: Oven

Manufacturer: Huida

Model: CS101-1E

Serial #: CS101-1E-B

Accuracy: Last Cal: 12/12/2013, Next Cal: 12/11/2014

Equipment #: HZ-THC-01

Description: Humidity transmitter

Manufacturer: Thermtron

Model: SM-8-8200

Serial #: 38846

Accuracy: Last Cal: 2/27/2014, Next Cal: 2/26/2015

Equipment #: HZ-HPM-01

Description: NA9636H

Manufacturer: Ainuo

Model: 6031A

Serial #: 089601091

Accuracy: Last Cal: 3/6/2014, Next Cal: 3/5/2015

Equipment #: HZ-MO-05

Description: Micro-ohmmeter

Manufacturer: Keithley

Model: 3706

Serial #: 1285188

Accuracy: Last Cal: 11/14/2013, Next Cal: 11/13/2014

Equipment #: HZ-TSC-01

Description: Vertical Thermal Shock Chamber

Manufacturer: Cincinnati Sub Zero

Model: VTS-3-6-6-SC/AC

Serial #: 10-VT14994

Accuracy: See Manual

... Last Cal: 06/26/2014, Next Cal: 06/25/2015

Equipment #: HZ-MO-01

Description: Multimeter /Data Acquisition System

Manufacturer: Keithley

Model: 2700

Serial #: 1199807

Accuracy: See Manual

... Last Cal: 07/01/2014, Next Cal: 06/30/2015

EQUIPMENT AND CALIBRATION SCHEDULES Continued**Equipment #:** PS-09**Description:** 50 Amp Power Supply**Manufacturer:** Agilent**Model:** AT-6032A**Serial #:** US38322853**Accuracy:** See Manual

... Last Cal: 07/02/2013, Next Cal: 07/01/2014

Equipment #: MO-9**Description:** Switch/Multimeter**Manufacturer:** Keithley**Model:** 2750**Serial #:** WDC-874817**Accuracy:** See Manual

... Last Cal: 08/21/2013, Next Cal: 08/21/2014

Equipment #: MO-11**Description:** Switch/Multimeter**Manufacturer:** Keithley**Model:** 3706**Serial #:** 120169**Accuracy:** See Manual

... Last Cal: 08/21/2013, Next Cal: 08/21/2014

Equipment #: SVC-01**Description:** Shock & Vibration Table**Manufacturer:** Data Physics**Model:** LE-DSA-10-20K**Serial #:** 10037**Accuracy:** See Manual

... Last Cal: 11/31/2013, Next Cal: 11/31/2014

Equipment #: ACLM-01**Description:** Accelerometer**Manufacturer:** PCB Piezotronics**Model:** 352C03**Serial #:** 115819**Accuracy:** See Manual

... Last Cal: 07/09/2014, Next Cal: 07/09/2015

Equipment #: ED-03**Description:** Event Detector**Manufacturer:** Analysis Tech**Model:** 32EHD**Serial #:** 1100604**Accuracy:** See Manual

... Last Cal: 06/04/2014, Next Cal: 06/04/2015